Keysight D9040EDPV eDP Test Application

Notices

Safety Notices

CAUTION

A **CAUTION** notice denotes a hazard. It calls attention to an operating procedure, practice, or the like that, if not correctly performed or adhered to, could result in damage to the product or loss of important data. Do not proceed beyond a **CAUTION** notice until the indicated conditions are fully understood and met.

WARNING

A WARNING notice denotes a hazard. It calls attention to an operating procedure, practice, or the like that, if not correctly performed or adhered to, could result in personal injury or death. Do not proceed beyond a WARNING notice until the indicated conditions are fully understood and met.

In This Book

This book is your guide to programming the Keysight Technologies D9040EDPV eDP Test Application.

· Chapter 1, "Introduction to Programming," starting on page 7, describes compliance application programming basics.

· Chapter 2, "Configuration Variables and Values," starting on page 9, Chapter 3, "Test Names and IDs," starting on page 45, Chapter 4, "Instruments," starting on page 83, and Chapter 5, "Message IDs," starting on page 85 provide information specific to programming the D9040EDPV eDP Test Application.

How to Use This Book

Programmers who are new to compliance application programming should read all of the chapters in order. Programmers who are already familiar with this may review chapters 2, 3, 4, and 5 for changes.

Contents

1 Introduction to Programming

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This chapter introduces the basics for remote programming a compliance/test application. The programming commands provide the means of remote control. Basic operations that you can do remotely with a computer and a compliance/test app running on an oscilloscope include:

- Launching and closing the application.
- Configuring the options.
- Running tests.
- Getting results.
- Controlling when and were dialogs get displayed
- Saving and loading projects.

You can accomplish other tasks by combining these functions.

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Remote Programming Toolkit

The majority of remote interface features are common across all the Keysight Technologies, Inc. family of compliance/test applications. Information on those features is provided in the N5452A Compliance Application Remote Programming Toolkit available for download from Keysight here: www.keysight.com/find/rpi. The D9040EDPV eDP Test Application uses Remote Interface Revision 7.2. The help files provided with the toolkit indicate which features are supported in this version.

In the toolkit, various documents refer to "application-specific configuration variables, test information, and instrument information". These are provided in Chapters 2, 3, and 4 of this document, and are also available directly from the application's user interface when the remote interface is enabled (View>Preferences::Remote tab::Show remote interface hints). See the toolkit for more information.

2 Configuration Variables and Values

The following table contains a description of each of the D9040EDPV eDP Test Application options that you may query or set remotely using the appropriate remote interface method. The columns contain this information:

- GUI Location — Describes which graphical user interface tab contains the control used to change the value.
- Label — Describes which graphical user interface control is used to change the value.
- Variable — The name to use with the SetConfig method.
- Values — The values to use with the SetConfig method.
- Description — The purpose or function of the variable.

For example, if the graphical user interface contains this control on the **Set Up** tab:

- Enable Advanced Features

then you would expect to see something like this in the table below:

Table 1 Example Configuration Variables and Values

GUI Location	Label	Variable	Values	Description
Set Up	Enable Advanced Features	EnableAdvanced	True, False	Enables a set of optional features.

and you would set the variable remotely using:

```
ARSL syntax
-----------
arsl -a ipaddress -c "SetConfig 'EnableAdvanced' 'True'"

C# syntax
```

```
---------
remoteAte.SetConfig("EnableAdvanced", "True");
```

Here are the actual configuration variables and values used by this application:

NOTE   Some of the values presented in the table below may not be available in certain configurations. Always perform a "test run" of your remote script using the application's graphical user interface to ensure the combinations of values in your program are valid.

NOTE   The file, "ConfigInfo.txt", which may be found in the same directory as this help file, contains all of the information found in the table below in a format suitable for parsing.

Table 2   Configuration Variables and Values

GUI Location	Label	Variable	Values	Description
Configure	AC Common Mode Noise Edges	ACCommonModeNoiseEdge	(Accepts user-defined text), 100, 1000, 10000, 100000, 200000	Set the number of edges measured for the AC Common Mode Noise Test.
Configure	AC Common Mode Noise Filter	ACCommonModeNoiseFilter	None, HighPassFilter, LowPassFilter	Select the type of filter used in AC Common Mode Noise Test.
Configure	AC Common Mode Noise Filter Cutoff Frequency	ACCommonModeNoiseFilterCutoffFrequency	(Accepts user-defined text), 50MHz, 500MHz, 1000MHz	Set the 3 dB cutoff frequency of the filter used in AC Common Mode Noise Test. This configuration only applicable when the [AC Common Mode Noise Filter] config variable is set to [High Pass Filter] or [Low Pass Filter]. Please specify the value in following format: "XMHz", "XkHz" or "XHz", where X is an integer.
Configure	AC Common Mode Noise Memory Depth (kpts)	ACCommonModeNoiseMemoryDepth	(Accepts user-defined text), 2000, 5000, 8000	Set the memory depth for each acquisition in AC Common Mode Noise Test. Unit: kpts.
Configure	AUX Channel Idle DC Offset	AUXIdleDCOffset	True, False	Select whether or not to remove the AUX channel idle DC offset for AUX Channel Tests.
Configure	AUX Channel Traffic Decode Count	AUXTrafficDecodeCount	(Accepts user-defined text), 10, 20, 50, 100, 200, 500, 1000	Set the total amount of AUX Channel traffic required for AUX Channel Sensitivity Test. This configuration only applicable when the [Test Method] configuration variable is set to oscilloscope decode method [Scope Method].

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	AUX Channel Traffic Prompt	PromptForAUX Traffic	true, false	Select whether or not to prompt the user to initiate AUX Channel traffic for AUX Channel Tests.
Configure	AUX Channel Voltage Swing Maximum Limit (V)	AUXSensitivity MaxVSwing	(Accepts user-defined text), 0.28, 0.26	Set the calibrated AUX Channel voltage swing maximum limit for AUX Channel Calibration Test. Unit: V.
Configure	AUX Channel Voltage Swing Minimum Limit (V)	AUXSensitivity MinVSwing	(Accepts user-defined text), 0.28, 0.24	Set the calibrated AUX Channel voltage swing minimum limit for AUX Channel Calibration Test. Unit: V.
Configure	AUX Clock Recovery Filter	AUXClockReco veryFilter	true, false	Select whether or not to apply low pass filter on the AUX Channel signal before recover the clock signal.
Configure	AUX Probe Check (AUX Channel Tests)	AUXProbeChec k	Enable, Disable	Select to enable or disable probe check for AUX Channel Tests.
Configure	AUX Sensitivity Calibration Acquisition	AUXSensitivity CalibrationAcq uisition	(Accepts user-defined text), 1, 3, 5, 10	Set the number of acquisition for AUX Channel Calibration Test.
Configure	Bandwidth Reduction	BWReduction	AUTO, 4.0E9, 6.0E9, 8.0E9, 13.0E9, 20.0E9, 32.0E9, MAX	Set the bandwidth for the acquisition setup of the oscilloscope. This configuration only applicable when the Enhance Bandwidth or Noise Reduction option is installed on the oscilloscope.
Configure	Cable Model Type	CableModelTyp e	ActualPhysicalCable, SoftwareCableModel	Select the type of cable model to be used for TP3 and TP3_EQ tests. Please select [Actual Physical Cable] if actual eDP cable is included in the connection for the test measurement. Please select [Software Cable Model] if eDP cable is not included in the connection for the test measurement. The eDP application will include the cable model specified by [Custom Cable Model File Name] config variable for the TP3 and TP3_EQ tests.
Configure	Channel Skew	ChannelSkew	Disable, Enable	Select to enable or disable channel skew. For [Disable], the skew of all the channels will be default to 0 before each run of the test.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Clock Recovery Damping Factor - HBR (Second Order PLL Only)	CDR_DampingFactor_HBR	(Accepts user-defined text), 1.43, 1.51, 1.6, N/A	Set the damping factor used by the second order PLL to recover the clock for HBR. This configuration only applicable when the [Clock Recovery Order] config variable is set to second order PLL clock recovery.
Configure	Clock Recovery Damping Factor - HBR2 (Second Order PLL Only)	CDR_DampingFactor_HBR2	(Accepts user-defined text), 1.0, 1.43, 1.51, 1.6, N/A	Set the damping factor used by the second order PLL to recover the clock for HBR2. This configuration only applicable when the [Clock Recovery Order] config variable is set to second order PLL clock recovery.
Configure	Clock Recovery Damping Factor - HBR3 (Second Order PLL Only)	CDR_DampingFactor_HBR3	(Accepts user-defined text), 1.0, 1.43, 1.51, 1.6, N/A	Set the damping factor used by the second order PLL to recover the clock for HBR3. This configuration only applicable when the [Clock Recovery Order] config variable is set to second order PLL clock recovery.
Configure	Clock Recovery Damping Factor - Link Rate 1 (Second Order PLL Only)	CDR_DampingFactor_LinkRate1	(Accepts user-defined text), 1.43, 1.51, 1.6, N/A	Set the damping factor used by the second order PLL to recover the clock for Link Rate 1. This configuration only applicable when the [Clock Recovery Order] config variable is set to second order PLL clock recovery.
Configure	Clock Recovery Damping Factor - Link Rate 2 (Second Order PLL Only)	CDR_DampingFactor_LinkRate2	(Accepts user-defined text), 1.43, 1.51, 1.6, N/A	Set the damping factor used by the second order PLL to recover the clock for Link Rate 2. This configuration only applicable when the [Clock Recovery Order] config variable is set to second order PLL clock recovery.
Configure	Clock Recovery Damping Factor - Link Rate 3 (Second Order PLL Only)	CDR_DampingFactor_LinkRate3	(Accepts user-defined text), 1.0, 1.43, 1.51, 1.6, N/A	Set the damping factor used by the second order PLL to recover the clock for Link Rate 3. This configuration only applicable when the [Clock Recovery Order] config variable is set to second order PLL clock recovery.
Configure	Clock Recovery Damping Factor - Link Rate 4 (Second Order PLL Only)	CDR_DampingFactor_LinkRate4	(Accepts user-defined text), 1.0, 1.43, 1.51, 1.6, N/A	Set the damping factor used by the second order PLL to recover the clock for Link Rate 4. This configuration only applicable when the [Clock Recovery Order] config variable is set to second order PLL clock recovery.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Clock Recovery Damping Factor - RBR (Second Order PLL Only)	CDR_DampingFactor_RBR	(Accepts user-defined text), 1.43, 1.51, 1.6, N/A	Set the damping factor used by the second order PLL to recover the clock for RBR. This configuration only applicable when the [Clock Recovery Order] config variable is set to second order PLL clock recovery.
Configure	Clock Recovery Loop Bandwidth - HBR	CDR_BW_HBR	(Accepts user-defined text), 20.0MHz, 10.0MHz	Set the 3 dB bandwidth of the loop filter used by the PLL to recover the clock for HBR. This configuration only applicable when the [Clock Recovery Settings Mode] config variable is set to [Auto]. Please specify the value in following format: "XMHz", "XkHz" or "XHz", where X is an integer.
Configure	Clock Recovery Loop Bandwidth - HBR2	CDR_BW_HBR2	(Accepts user-defined text), 20.0MHz, 10.0MHz	Set the 3 dB bandwidth of the loop filter used by the PLL to recover the clock for HBR2. This configuration only applicable when the [Clock Recovery Settings Mode] config variable is set to [Auto]. Please specify the value in following format: "XMHz", "XkHz" or "XHz", where X is an integer.
Configure	Clock Recovery Loop Bandwidth - HBR3	CDR_BW_HBR3	(Accepts user-defined text), 20.0MHz, 15.0MHz, 10.0MHz	Set the 3 dB bandwidth of the loop filter used by the PLL to recover the clock for HBR3. This configuration only applicable when the [Clock Recovery Settings Mode] config variable is set to [Auto]. Please specify the value in following format: "XMHz", "XkHz" or "XHz", where X is an integer.
Configure	Clock Recovery Loop Bandwidth - Link Rate 1	CDR_BW_LinkRate1	(Accepts user-defined text), 10.8MHz, 5.4MHz	Set the 3 dB bandwidth of the loop filter used by the PLL to recover the clock for Link Rate 1. This configuration only applicable when the [Clock Recovery Settings Mode] config variable is set to [Manual]. Please specify the value in following format: "XMHz", "XkHz" or "XHz", where X is an integer.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Clock Recovery Loop Bandwidth - Link Rate 2	CDR_BW_LinkRate2	(Accepts user-defined text), 20.0MHz, 10.0MHz	Set the 3 dB bandwidth of the loop filter used by the PLL to recover the clock for Link Rate 2. This configuration only applicable when the [Clock Recovery Settings Mode] config variable is set to [Manual]. Please specify the value in following format: "XMHz", "XkHz" or "XHz", where X is an integer.
Configure	Clock Recovery Loop Bandwidth - Link Rate 3	CDR_BW_LinkRate3	(Accepts user-defined text), 20.0MHz, 10.0MHz	Set the 3 dB bandwidth of the loop filter used by the PLL to recover the clock for Link Rate 3. This configuration only applicable when the [Clock Recovery Settings Mode] config variable is set to [Manual]. Please specify the value in following format: "XMHz", "XkHz" or "XHz", where X is an integer.
Configure	Clock Recovery Loop Bandwidth - Link Rate 4	CDR_BW_LinkRate4	(Accepts user-defined text), 20.0MHz, 10.0MHz	Set the 3 dB bandwidth of the loop filter used by the PLL to recover the clock for Link Rate 4. This configuration only applicable when the [Clock Recovery Settings Mode] config variable is set to [Manual]. Please specify the value in following format: "XMHz", "XkHz" or "XHz", where X is an integer.
Configure	Clock Recovery Loop Bandwidth - RBR	CDR_BW_RBR	(Accepts user-defined text), 10.8MHz, 5.4MHz	Set the 3 dB bandwidth of the loop filter used by the PLL to recover the clock for RBR. This configuration only applicable when the [Clock Recovery Settings Mode] config variable is set to [Auto]. Please specify the value in following format: "XMHz", "XkHz" or "XHz", where X is an integer.
Configure	Clock Recovery Loop Bandwidth Correction Mode	CDR_BW_CorrectionMode	Enable, Disable	Enable or disable clock recovery loop bandwidth correction mode. This configuration only applicable when the [Clock Recovery Order] config variable is set to second order PLL clock recovery.
Configure	Clock Recovery Order	ClockRecoveryOrder	1st, 2nd	Set the order of PLL clock recovery to either first order PLL clock recovery method or second order PLL clock recovery method.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Clock Recovery Settings Mode	ClockRecovery SettingsMode	Auto, Manual	Set the mode for clock recovery setting to either [Auto] mode or [Manual] mode. For [Auto] mode, the clock recovery setting is selected based on the bit rate measured. For [Manual] mode, the clock recovery setting is selected based on the link rate.
Configure	Custom Cable Model File Name	CustomCableM odelFileName	(Accepts user-defined text), Custom	Set the custom cable model s-parameter file name to be used for TP3 and TP3_EQ tests. The s-parameter file must be copy to the "C:\ProgramData\Keysight\ Infiniium\Apps\eDPTest\App\ S-Parameter\Cable Model\Custom" folder. This configuration only applicable when the [Cable Model Type] config variable is set to [Software Cable Model].
Configure	De-Embed Delay	DeEmbedDelay	(Accepts user-defined text), True, False	Select whether to include or exclude delay for fixture de-embedding and/or cable model embedding.
Configure	Decode Filter	AUXDecodeFilt er	true, false	Select whether or not to apply filter before AUX Channel traffic decode for AUX Channel Sensitivity Test.
Configure	Equalizer Enable	EqualizerEnabl e	True, False	Select to enable or disable equalizer when performing tests at TP3_EQ test point. For [True], the equalizer will be enabled when performing tests at TP3_EQ test point. For [False], the equalizer will disabled when performing tests at TP3_EQ test point.
Configure	Expert Mode	ExpertMode	Off, On	Select to enable or disable expert mode.
Configure	Eye Diagram Custom Eye Mask	EyeDiagramCus tomEyeMask	False, True	Select to enable custom eye mask to be used in Eye Diagram Test.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Eye Diagram Eye Mask Movement	EyeDiagramEyeMaskMovement		Select the type of movement performed on the eye mask used in Eye Diagram Test. For [Fixed] mode, the mask will not shifted and aligned. For [Find Pass] mode, the mask will automatically shifted and aligned horizontally within +/-0.25UI until no violation occurs. For [Find Margin] mode, the mask will automatically shifted and aligned horizontally within +/-0.25UI to search for maximum margin with no violation occurs.
Configure	Eye Diagram Eye Mask Scale	EyeDiagramEyeMaskScale	Absolute, Normalized	Select the type of scale performed on the eye mask used in Eye Diagram Test.
Configure	Eye Diagram Folding Bits	EyeDiagramFoldingBits	AUTO, BOTH, DEEMphasis, TRANsition	Select to folding bits used in Eye Diagram Test. For [Auto], [Both] folding bits will be used for Pre-Emphasis Level 0 and [Transition] folding bits will be used for other Pre-Emphasis Level.
Configure	Eye Diagram Include Random Noise	EyeDiagramIncludeRandomNoise	False, True	Select to include random noise on the eye mask used in Eye Diagram Test. This configuration only applicable when the [Eye Diagram Eye Mask Height Location] config variable is set to [Dynamic].
Configure	Eye Diagram Memory Depth (kpts)	EyeDiagramMemoryDepth	(Accepts user-defined text), 2000, 5000, 8000	Set the memory depth for each acquisition in Eye Diagram Test. Unit: kpts.
Configure	Eye Diagram Passing End Location (UI)	EyeDiagramPassEndLocation	(Accepts user-defined text), 0.625	Set the end passing unit interval location for Eye Diagram Test. Unit: UI.
Configure	Eye Diagram Passing Start Location (UI)	EyeDiagramPassStartLocation	(Accepts user-defined text), 0.375	Set the start passing unit interval location for Eye Diagram Test. Unit: UI.
Configure	Eye Diagram UI Count	EyeDiagramUICount	10000, 100000, 1000000, 10000000, 100000000, 1000000000	Select the number of UI measured for Eye Diagram Test.
Configure	Eye Mask Center Vertical Position	AUXEyeMaskCenter	0 V, AutoOffset	Select the vertical position of the eye mask center for AUX Channel Tests.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Eye Mask Width Reference	AUXEyeMaskWidthReference	Nominal, Average	Select the eye width reference of the eye mask for AUX Channel Tests to either based on nominal data rate (Nominal) or measured data rate (Average).
Configure	Eye Width	DFE_EyeWidth	(Accepts user-defined text), 0	Set the eye width to be used for the optimization of the DFE equalizer when running tests at TP3_EQ test point. This configuration only applicable when the DFE Mode is set to Auto. Unit: UI.
Configure	Fall Time Location (D10.2)	FallTimeLocationD10_2	(Accepts user-defined text), 1	Set the zero based pattern bit location used for D10.2 fall time measurement in Fall Time Test.
Configure	Fall Time Location (Other Pattern)	FallTimeLocationOtherPattern	(Accepts user-defined text), 1	Set the zero based pattern bit location used for Other Pattern fall time measurement in Fall Time Test.
Configure	Fall Time Location (PLTPAT)	FallTimeLocationPLTPAT	(Accepts user-defined text), 1	Set the zero based pattern bit location used for PLTPAT fall time measurement in Fall Time Test.
Configure	Fall Time Location (PRBS 7)	FallTimeLocationPRBS7	(Accepts user-defined text), 1	Set the zero based pattern bit location used for PRBS 7 fall time measurement in Fall Time Test.
Configure	Fall Time Location (PRBS 9)	FallTimeLocationPRBS9	(Accepts user-defined text), 1	Set the zero based pattern bit location used for PRBS 9 fall time measurement in Fall Time Test.
Configure	Fall Time Location (Random Pattern)	FallTimeLocationRandomPattern	(Accepts user-defined text), 1	Set the zero based pattern bit location used for Random Pattern fall time measurement in Fall Time Test.
Configure	Fall Time Location (TPS4)	FallTimeLocationTPS4	(Accepts user-defined text), 1	Set the zero based pattern bit location used for TPS4 fall time measurement in Fall Time Test.
Configure	Fall Time Pattern (D10.2)	FallTimePatternD10_2	(Accepts user-defined text), 10	Set the triggering pattern used for D10.2 fall time measurement in Fall Time Test.
Configure	Fall Time Pattern (Other Pattern)	FallTimePatternOtherPattern	(Accepts user-defined text), 10	Set the triggering pattern used for Other Pattern fall time measurement in Fall Time Test.
Configure	Fall Time Pattern (PLTPAT)	FallTimePatternPLTPAT	(Accepts user-defined text), 100000	Set the triggering pattern used for PLTPAT fall time measurement in Fall Time Test.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Fall Time Pattern (PRBS 7)	FallTimePattern PRBS7	(Accepts user-defined text), 10	Set the triggering pattern used for PRBS 7 fall time measurement in Fall Time Test.
Configure	Fall Time Pattern (PRBS 9)	FallTimePattern PRBS9	(Accepts user-defined text), 10	Set the triggering pattern used for PRBS 9 fall time measurement in Fall Time Test.
Configure	Fall Time Pattern (Random Pattern)	FallTimePattern RandomPattern	(Accepts user-defined text), 10	Set the triggering pattern used for Random Pattern fall time measurement in Fall Time Test.
Configure	Fall Time Pattern (TPS4)	FallTimePattern TPS4	(Accepts user-defined text), 10	Set the triggering pattern used for TPS4 fall time measurement in Fall Time Test.
Configure	Inter Pair Skew Edges	InterPairSkewE dge	(Accepts user-defined text), 100, 500, 1000	Set the number of edges measured for the Inter Pair Skew Test.
Configure	Inter Pair Skew Maximum Retries	InterPairSkew MaxRetries	20, 50, 100	Set the number of retries for the Inter Pair Skew Test.
Configure	Inter Pair Skew Memory Depth (kpts)	InterPairSkew MemoryDepth	(Accepts user-defined text), 2000, 5000, 8000	Set the memory depth for each acquisition in Inter Pair Skew Test. Unit: kpts.
Configure	Inter Pair Skew Middle Threshold Type	InterPairSkew MiddleThreshol dType	FixedVoltage, ThresholdMode	Select the type of middle threshold for the Inter Pair Skew Test.
Configure	Inter Pair Skew Middle Threshold Voltage (V)	InterPairSkew MiddleThreshol dVoltage	(Accepts user-defined text), 0	Set the middle threshold voltage for the Inter Pair Skew Test. Unit: Volt. This configuration only applicable when the [Inter Pair Skew Middle Threshold] config variable is set to [Fixed Voltage].
Configure	Inter Pair Skew Pattern (HBR2CPAT)	InterPairSkewP atternHBR2CP AT	(Accepts user-defined text), 0000001, 011111	Set the triggering pattern used for HBR2CPAT inter pair skew measurement in Inter Pair Skew Test.
Configure	Inter Pair Skew Pattern (Other Pattern)	InterPairSkewP atternOtherPatt ern	(Accepts user-defined text), 0000001, 0000111	Set the triggering pattern used for Other Pattern inter pair skew measurement in Inter Pair Skew Test.
Configure	Inter Pair Skew Pattern (PRBS 7)	InterPairSkewP atternPRBS7	(Accepts user-defined text), 0000001, 0000111	Set the triggering pattern used for PRBS 7 inter pair skew measurement in Inter Pair Skew Test.
Configure	Inter Pair Skew Pattern (PRBS 9)	InterPairSkewP atternPRBS9	(Accepts user-defined text), 0000001, 0000111	Set the triggering pattern used for PRBS 9 inter pair skew measurement in Inter Pair Skew Test.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Inter Pair Skew Pattern (Random Pattern)	InterPairSkewPatternRandomPattern	(Accepts user-defined text), 0000001, 0000111	Set the triggering pattern used for Random Pattern inter pair skew measurement in Inter Pair Skew Test.
Configure	Inter Pair Skew Pattern (TPS4)	InterPairSkewPatternTPS4	(Accepts user-defined text), 0000001, 011111	Set the triggering pattern used for TPS4 inter pair skew measurement in Inter Pair Skew Test.
Configure	Inter Pair Skew Pattern Match Bit Number	InterPairSkewPatternMatchBitNum	(Accepts user-defined text), 1, 10, 100, 200	Set the number of bit for pattern matching in Inter Pair Skew Test.
Configure	Inter Pair Skew Search Mode	InterPairSkewSearchMode	Closest, Next Closest	Select the mode for the pattern search in Inter Pair Skew Test. For [Closest], the eDP application will look for the closest match pattern either before or after the reference lane. For [Next Closest], the eDP application will look for the closest match pattern after the reference lane only.
Configure	Intra Pair Skew Edges	IntraPairSkewEdge	(Accepts user-defined text), 100, 500, 1000	Set the number of edges measured for the Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Fall Lane- Rise Location (D10.2)	IntraPairSkewFallRiseLocationD10_2	(Accepts user-defined text), 1	Set the zero based pattern bit location used for D10.2 Lane+ fall to Lane- rise skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Fall Lane- Rise Location (HBR2CPAT)	IntraPairSkewFallRiseLocationHBR2CPAT	(Accepts user-defined text), 1	Set the zero based pattern bit location used for HBR2CPAT Lane+ fall to Lane- rise skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Fall Lane- Rise Location (TPS4)	IntraPairSkewFallRiseLocationTPS4	(Accepts user-defined text), 1	Set the zero based pattern bit location used for TPS4 Lane+ fall to Lane- rise skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Fall Lane- Rise Pattern (D10.2)	IntraPairSkewFallRisePatternD10_2	(Accepts user-defined text), 10	Set the triggering pattern used for D10.2 Lane+ fall to Lane- rise skew measurement in Intra Pair Skew Test.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Intra Pair Skew Lane+ Fall Lane- Rise Pattern (HBR2CPAT)	IntraPairSkewFallRisePatternHBR2CPAT	(Accepts user-defined text), 10	Set the triggering pattern used for HBR2CPAT Lane+ fall to Lane- rise skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Fall Lane- Rise Pattern (TPS4)	IntraPairSkewFallRisePatternTPS4	(Accepts user-defined text), 10	Set the triggering pattern used for TPS4 Lane+ fall to Lane- rise skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Rise Lane- Fall Location (D10.2)	IntraPairSkewRiseFallLocationD10_2	(Accepts user-defined text), 1	Set the zero based pattern bit location used for D10.2 Lane+ rise to Lane- fall skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Rise Lane- Fall Location (HBR2CPAT)	IntraPairSkewRiseFallLocationHBR2CPAT	(Accepts user-defined text), 1	Set the zero based pattern bit location used for HBR2CPAT Lane+ rise to Lane- fall skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Rise Lane- Fall Location (TPS4)	IntraPairSkewRiseFallLocationTPS4	(Accepts user-defined text), 1	Set the zero based pattern bit location used for TPS4 Lane+ rise to Lane- fall skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Rise Lane- Fall Pattern (D10.2)	IntraPairSkewRiseFallPatternD10_2	(Accepts user-defined text), 01	Set the triggering pattern used for D10.2 Lane+ rise to Lane- fall skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Rise Lane- Fall Pattern (HBR2CPAT)	IntraPairSkewRiseFallPatternHBR2CPAT	(Accepts user-defined text), 01	Set the triggering pattern used for HBR2CPAT Lane+ rise to Lane- fall skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Lane+ Rise Lane- Fall Pattern (TPS4)	IntraPairSkewRiseFallPatternTPS4	(Accepts user-defined text), 01	Set the triggering pattern used for TPS4 Lane+ rise to Lane- fall skew measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew Memory Depth (kpts)	IntraPairSkewMemoryDepth	(Accepts user-defined text), 100, 500, 1000	Set the memory depth for each acquisition in Intra Pair Skew Test. Unit: kpts.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Intra Pair Skew VH Location (D10.2)	IntraPairSkewVHLocationD10_2	(Accepts user-defined text), 1.6, 1.75	Set the pattern bit location used for D10.2 VH transition measurement in Intra Pair Skew Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Intra Pair Skew VH Location (HBR2CPAT)	IntraPairSkewVHLocationHBR2CPAT	(Accepts user-defined text), 1.6, 1.75	Set the pattern bit location used for HBR2CPAT VH transition measurement in Intra Pair Skew Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Intra Pair Skew VH Location (TPS4)	IntraPairSkewVHLocationTPS4	(Accepts user-defined text), 1.6, 1.75	Set the pattern bit location used for TPS4 VH transition measurement in Intra Pair Skew Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Intra Pair Skew VH Pattern (D10.2)	IntraPairSkewVHPatternD10_2	(Accepts user-defined text), 01	Set the triggering pattern used for D10.2 VH measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew VH Pattern (HBR2CPAT)	IntraPairSkewVHPatternHBR2CPAT	(Accepts user-defined text), 01	Set the triggering pattern used for HBR2CPAT VH measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew VH Pattern (TPS4)	IntraPairSkewVHPatternTPS4	(Accepts user-defined text), 01	Set the triggering pattern used for TPS4 VH measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew VL Location (D10.2)	IntraPairSkewVLLocationD10_2	(Accepts user-defined text), 1.6, 1.75	Set the pattern bit location used for D10.2 VL transition measurement in Intra Pair Skew Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Intra Pair Skew VL Location (HBR2CPAT)	IntraPairSkewVLLocationHBR2CPAT	(Accepts user-defined text), 1.6, 1.75	Set the pattern bit location used for HBR2CPAT VL transition measurement in Intra Pair Skew Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Intra Pair Skew VL Location (TPS4)	IntraPairSkewVLLocationTPS4	(Accepts user-defined text), 1.6, 1.75	Set the pattern bit location used for TPS4 VL transition measurement in Intra Pair Skew Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Intra Pair Skew VL Pattern (D10.2)	IntraPairSkewVLPatternD10_2	(Accepts user-defined text), 10	Set the triggering pattern used for D10.2 VL measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew VL Pattern (HBR2CPAT)	IntraPairSkewVLPatternHBR2CPAT	(Accepts user-defined text), 10	Set the triggering pattern used for HBR2CPAT VL measurement in Intra Pair Skew Test.
Configure	Intra Pair Skew VL Pattern (TPS4)	IntraPairSkewVLPatternTPS4	(Accepts user-defined text), 10	Set the triggering pattern used for TPS4 VL measurement in Intra Pair Skew Test.
Configure	Jitter Bit Error Rate (HBR)	JitterBER_HBR	E6, E7, E8, E9, E10, E11, E12, E13, E14	Select the bit error rate (BER) for the extrapolation of total jitter for HBR.
Configure	Jitter Bit Error Rate (HBR2)	JitterBER_HBR2	E6, E7, E8, E9, E10, E11, E12, E13, E14	Select the bit error rate (BER) for the extrapolation of total jitter for HBR2.
Configure	Jitter Bit Error Rate (HBR3)	JitterBER_HBR3	E6, E7, E8, E9, E10, E11, E12, E13, E14	Select the bit error rate (BER) for the extrapolation of total jitter for HBR3.
Configure	Jitter Bit Error Rate (RBR)	JitterBER_RBR	E6, E7, E8, E9, E10, E11, E12, E13, E14	Select the bit error rate (BER) for the extrapolation of total jitter for RBR.
Configure	Jitter ISI Filter Lag	JitterISIFilterLag	(Accepts user-defined text), 5, 6	Select the ISI filter lag used for the jitter separation test. This configuration only applicable when the [Jitter Pattern Length] config variable is set to [Arbitrary].
Configure	Jitter ISI Filter Lead	JitterISIFilterLead	(Accepts user-defined text), -2, -3	Select the ISI filter lead used for the jitter separation test. This configuration only applicable when the [Jitter Pattern Length] config variable is set to [Arbitrary].
Configure	Jitter Memory Depth (kpts)	JitterMemoryDepth	(Accepts user-defined text), 2000, 5000, 8000	Set the memory depth for each acquisition in jitter separation test. Unit: kpts.
Configure	Jitter Pattern Length	JitterPatternLength	Arbitrary, Periodic	Select the pattern length used for the jitter separation test.
Configure	Jitter Separation Edges	JitterSeparationEdge	(Accepts user-defined text), 10000, 50000, 1000000	Set the number of edges measured for the jitter separation test.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Level Memory Depth (kpts)	LevelMemoryDepth	(Accepts user-defined text), 100, 500, 1000	Set the memory depth for each acquisition to be averaged and measured in Differential Voltage Level Test and Pre-Emphasis Level Test. Unit: kpts.
Configure	Level Pattern Count	LevelPatternCount	(Accepts user-defined text), 100, 500, 1000	Set the number of patterns to be averaged and measured in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VH Non Transition Location (HBR2CPAT)	LevelVHNonTransLocationHBR2CPAT	(Accepts user-defined text), 2.5, 5.5	Set the pattern bit location used for HBR2CPAT VH non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Non Transition Location (Other Pattern)	LevelVHNonTransLocationOtherPattern	(Accepts user-defined text), 3.5, 6.5	Set the pattern bit location used for Other Pattern VH non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Non Transition Location (PLTPAT)	LevelVHNonTransLocationPLTPAT	(Accepts user-defined text), 2.5, 5.5	Set the pattern bit location used for PLTPAT VH non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Non Transition Location (PRBS 7)	LevelVHNonTransLocationPRBS7	(Accepts user-defined text), 3.5, 6.5	Set the pattern bit location used for PRBS 7 VH non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Non Transition Location (PRBS 9)	LevelVHNonTransLocationPRBS9	(Accepts user-defined text), 3.5, 6.5	Set the pattern bit location used for PRBS 9 VH non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Level VH Non Transition Location (Random Pattern)	LevelVHNonTransLocationRandomPattern	(Accepts user-defined text), 3.5, 6.5	Set the pattern bit location used for Random Pattern VH non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Non Transition Location (TPS4)	LevelVHNonTransLocationTPS4	(Accepts user-defined text), 2.5, 5.5	Set the pattern bit location used for TPS4 VH non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Pattern (HBR2CPAT)	LevelVHPatternHBR2CPAT	(Accepts user-defined text), 011111	Set the triggering pattern used for HBR2CPAT VH measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VH Pattern (Other Pattern)	LevelVHPatternOtherPattern	(Accepts user-defined text), 01111111	Set the triggering pattern used for Other Pattern VH measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VH Pattern (PLTPAT)	LevelVHPatternPLTPAT	(Accepts user-defined text), 011111	Set the triggering pattern used for PLTPAT VH measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VH Pattern (PRBS 7)	LevelVHPatternPRBS7	(Accepts user-defined text), 01111111	Set the triggering pattern used for PRBS 7 VH measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VH Pattern (PRBS 9)	LevelVHPatternPRBS9	(Accepts user-defined text), 01111111	Set the triggering pattern used for PRBS 9 VH measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VH Pattern (Random Pattern)	LevelVHPatternRandomPattern	(Accepts user-defined text), 01111111	Set the triggering pattern used for Random Pattern VH measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VH Pattern (TPS4)	LevelVHPatternTPS4	(Accepts user-defined text), 011111	Set the triggering pattern used for TPS4 VH measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Level VH Transition Location (HBR2CPAT)	LevelVHTransLocationHBR2CPAT	(Accepts user-defined text), 1.4, 1.7	Set the pattern bit location used for HBR2CPAT VH transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Transition Location (Other Pattern)	LevelVHTransLocationOtherPattern	(Accepts user-defined text), 1.4, 1.7	Set the pattern bit location used for Other Pattern VH transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Transition Location (PLTPAT)	LevelVHTransLocationPLTPAT	(Accepts user-defined text), 1.4, 1.7	Set the pattern bit location used for PLTPAT VH transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Transition Location (PRBS 7)	LevelVHTransLocationPRBS7	(Accepts user-defined text), 1.4, 1.7	Set the pattern bit location used for PRBS 7 VH transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Transition Location (PRBS 9)	LevelVHTransLocationPRBS9	(Accepts user-defined text), 1.4, 1.7	Set the pattern bit location used for PRBS 9 VH transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VH Transition Location (Random Pattern)	LevelVHTransLocationRandomPattern	(Accepts user-defined text), 1.4, 1.7	Set the pattern bit location used for Random Pattern VH transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Level VH Transition Location (TPS4)	LevelVHTransLocationTPS4	(Accepts user-defined text), 1.4, 1.7	Set the pattern bit location used for TPS4 VH transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Non Transition Location (HBR2CPAT)	LevelVLNonTransLocationHBR2CPAT	(Accepts user-defined text), 4.5, 6.5	Set the pattern bit location used for HBR2CPAT VL non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Non Transition Location (Other Pattern)	LevelVLNonTransLocationOtherPattern	(Accepts user-defined text), 4.5, 6.5	Set the pattern bit location used for Other Pattern VL non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Non Transition Location (PLTPAT)	LevelVLNonTransLocationPLTPAT	(Accepts user-defined text), 2.5, 5.5	Set the pattern bit location used for PLTPAT VL non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Non Transition Location (PRBS 7)	LevelVLNonTransLocationPRBS7	(Accepts user-defined text), 4.5, 6.5	Set the pattern bit location used for PRBS 7 VL non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Non Transition Location (PRBS 9)	LevelVLNonTransLocationPRBS9	(Accepts user-defined text), 4.5, 6.5	Set the pattern bit location used for PRBS 9 VL non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.

Table 2 Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Level VL Non Transition Location (Random Pattern)	LevelVLNonTransLocationRandomPattern	(Accepts user-defined text), 4.5, 6.5	Set the pattern bit location used for Random Pattern VL non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Non Transition Location (TPS4)	LevelVLNonTransLocationTPS4	(Accepts user-defined text), 4.5, 6.5	Set the pattern bit location used for TPS4 VL non transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Pattern (HBR2CPAT)	LevelVLPatternHBR2CPAT	(Accepts user-defined text), 10100001	Set the triggering pattern used for HBR2CPAT VL measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VL Pattern (Other Pattern)	LevelVLPatternOtherPattern	(Accepts user-defined text), 10100001	Set the triggering pattern used for Other Pattern VL measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VL Pattern (PLTPAT)	LevelVLPatternPLTPAT	(Accepts user-defined text), 100000	Set the triggering pattern used for PLTPAT VL measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VL Pattern (PRBS 7)	LevelVLPatternPRBS7	(Accepts user-defined text), 10100001	Set the triggering pattern used for PRBS 7 VL measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VL Pattern (PRBS 9)	LevelVLPatternPRBS9	(Accepts user-defined text), 10100001	Set the triggering pattern used for PRBS 9 VL measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VL Pattern (Random Pattern)	LevelVLPatternRandomPattern	(Accepts user-defined text), 10100001	Set the triggering pattern used for Random Pattern VL measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.
Configure	Level VL Pattern (TPS4)	LevelVLPatternTPS4	(Accepts user-defined text), 10100001	Set the triggering pattern used for TPS4 VL measurement in Differential Voltage Level Test and Pre-Emphasis Level Test.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Level VL Transition Location (HBR2CPAT)	LevelVLTransLocationHBR2CPAT	(Accepts user-defined text), 3.4, 1.7	Set the pattern bit location used for HBR2CPAT VL transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Transition Location (Other Pattern)	LevelVLTransLocationOtherPattern	(Accepts user-defined text), 3.4, 3.7	Set the pattern bit location used for Other Pattern VL transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Transition Location (PLTPAT)	LevelVLTransLocationPLTPAT	(Accepts user-defined text), 1.4, 1.7	Set the pattern bit location used for PLTPAT VL transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Transition Location (PRBS 7)	LevelVLTransLocationPRBS7	(Accepts user-defined text), 3.4, 3.7	Set the pattern bit location used for PRBS 7 VL transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Transition Location (PRBS 9)	LevelVLTransLocationPRBS9	(Accepts user-defined text), 3.4, 3.7	Set the pattern bit location used for PRBS 9 VL transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Level VL Transition Location (Random Pattern)	LevelVLTransLocationRandomPattern	(Accepts user-defined text), 3.4, 3.7	Set the pattern bit location used for Random Pattern VL transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Level VL Transition Location (TPS4)	LevelVLTransLocationTPS4	(Accepts user-defined text), 3.4, 1.7	Set the pattern bit location used for TPS4 VL transition measurement in Differential Voltage Level Test and Pre-Emphasis Level Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Max Tap Value	DFE_MaxTapValue	(Accepts user-defined text), 1.000	Set the maximum tap value to be used for the optimization of the DFE equalizer when running tests at TP3_EQ test point. This configuration only applicable when the DFE Mode is set to Auto.
Configure	Maximum Memory Depth (Mpoints)	MaximumMemoryDepth	(Accepts user-defined text), 8.0, 10.0, 20.0, 30.0, 12.8, 16.0, 32.0, 48.0	Set the maximum memory depth limit for the acquisition setup of the oscilloscope for Physical Layer Tests. Unit: Mpoints.
Configure	Maximum Sampling Rate (GSa/s)	MaximumSamplingRate	20.0, 40.0, 80.0, 32.0, 64.0, 128.0	Set the maximum sampling rate for the acquisition setup of the oscilloscope for Physical Layer Tests. Unit: GSa/s.
Configure	Memory Depth (Points) (AUX Channel Sensitivity Test)	AUXSensitivityMemDepth	(Accepts user-defined text), 2000000, 5000000, 10000000, 20000000, 3200000, 8000000, 16000000, 32000000	Set the acquisition memory depth of the oscilloscope for AUX Channel Sensitivity Test. Unit: Points.
Configure	Memory Depth (points)	MemoryDepth	3000000, 5000000, 4800000, 8000000	Set the memory depth for the acquisition setup of the oscilloscope. Unit: points.
Configure	Memory Depth (points) (AUX Channel Tests)	AUXMemDepth	(Accepts user-defined text), 200000, 500000, 1000000, 2000000, 4000000, 5000000, 10000000, 20000000, 40000000, 320000, 800000, 1600000, 3200000, 6400000, 8000000, 16000000, 32000000, 64000000	Set the acquisition memory depth of the oscilloscope for AUX Channel Tests. Unit: points.
Configure	Min Tap Value	DFE_MinTapValue	(Accepts user-defined text), 0	Set the minimum tap value to be used for the optimization of the DFE equalizer when running tests at TP3_EQ test point. This configuration only applicable when the DFE Mode is set to Auto.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Minimum Failure Required	AUXMaxFailAcquisition	(Accepts user-defined text), 10, 100, 1000	Set the minimum number of acquisition to be analyze before test exit if AUX Channel Sensitivity Test fail. This configuration allows the user to stop the AUX Channel traffic decode immediately after the test fail to save test time. Unit: us.
Configure	Number of Acquisition (AUX Channel Tests)	AUXEyeAcquisition	(Accepts user-defined text), 1, 5, 10, 20	Set the number of acquisition needed for AUX Channel Tests.
Configure	Pattern Check	EnableSignalCheck	1.0, 0.0	Select to enable or disable pattern checking. When pattern checking is enabled, the input signal is pre-tested and verified to be within a reasonable range of timing and voltage limits. This can be useful for detecting problems like cabling errors before a test is run.
Configure	Pattern Decode Method	PatternDecodeMethod	10, 1, 2	Select the method to decode the serial data pattern for pattern validation. For [Auto], [Method 1] is used for HBR2CPAT and equalizer and [Method 2] is used for other pattern. For [Method 1], waveform data is used to decode for serial data pattern. For [Method 2], TEdge measurement is used to decode for serial data pattern.
Configure	Probe External Scaling (Single-Ended)	ProbeExternalScalingSingleEnded	Disable, Enable	Select to enable or disable probe external scaling. For [Disable], the probe external scaling will be default to 0 before each run of the test. This configuration only applicable when Single-Ended connection type is used.
Configure	Reference Device AUX Channel Voltage Swing (mV)	AUXSensitivityTestLevel	(Accepts user-defined text), 240, 250, 260, 270	Set the AUX Channel voltage swing set to the reference device for AUX Channel Calibration Test. Unit: mV.
Configure	Rise Time Location (D10.2)	RiseTimeLocationD10_2	(Accepts user-defined text), 1	Set the zero based pattern bit location used for D10.2 rise time measurement in Rise Time Test.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Rise Time Location (HBR2CPAT)	RiseTimeLocationHBR2CPAT	(Accepts user-defined text), 1	Set the zero based pattern bit location used for HBR2CPAT rise time measurement in Rise Time Test.
Configure	Rise Time Location (Other Pattern)	RiseTimeLocationOtherPattern	(Accepts user-defined text), 1	Set the zero based pattern bit location used for Other Pattern rise time measurement in Rise Time Test.
Configure	Rise Time Location (PLTPAT)	RiseTimeLocationPLTPAT	(Accepts user-defined text), 1	Set the zero based pattern bit location used for PLTPAT rise time measurement in Rise Time Test.
Configure	Rise Time Location (PRBS 7)	RiseTimeLocationPRBS7	(Accepts user-defined text), 1	Set the zero based pattern bit location used for PRBS 7 rise time measurement in Rise Time Test.
Configure	Rise Time Location (PRBS 9)	RiseTimeLocationPRBS9	(Accepts user-defined text), 1	Set the zero based pattern bit location used for PRBS 9 rise time measurement in Rise Time Test.
Configure	Rise Time Location (Random Pattern)	RiseTimeLocationRandomPattern	(Accepts user-defined text), 1	Set the zero based pattern bit location used for Random Pattern rise time measurement in Rise Time Test.
Configure	Rise Time Location (TPS4)	RiseTimeLocationTPS4	(Accepts user-defined text), 1	Set the zero based pattern bit location used for PLTPAT rise time measurement in Rise Time Test.
Configure	Rise Time Pattern (D10.2)	RiseTimePatternD10_2	(Accepts user-defined text), 01	Set the triggering pattern used for D10.2 rise time measurement in Rise Time Test.
Configure	Rise Time Pattern (HBR2CPAT)	RiseTimePatternHBR2CPAT	(Accepts user-defined text), 01	Set the triggering pattern used for HBR2CPAT rise time measurement in Rise Time Test.
Configure	Rise Time Pattern (Other Pattern)	RiseTimePatternOtherPattern	(Accepts user-defined text), 01	Set the triggering pattern used for Other Pattern rise time measurement in Rise Time Test.
Configure	Rise Time Pattern (PLTPAT)	RiseTimePatternPLTPAT	(Accepts user-defined text), 011111	Set the triggering pattern used for PLTPAT rise time measurement in Rise Time Test.
Configure	Rise Time Pattern (PRBS 7)	RiseTimePatternPRBS7	(Accepts user-defined text), 01	Set the triggering pattern used for PRBS 7 rise time measurement in Rise Time Test.
Configure	Rise Time Pattern (PRBS 9)	RiseTimePatternPRBS9	(Accepts user-defined text), 01	Set the triggering pattern used for PRBS 9 rise time measurement in Rise Time Test.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Rise Time Pattern (Random Pattern)	RiseTimePatternRandomPattern	(Accepts user-defined text), 01	Set the triggering pattern used for Random Pattern rise time measurement in Rise Time Test.
Configure	Rise Time Pattern (TPS4)	RiseTimePatternTPS4	(Accepts user-defined text), 01	Set the triggering pattern used for TPS4 rise time measurement in Rise Time Test.
Configure	Rise and Fall Time Mismatch Edges	RiseFallTimeMismatchEdge	(Accepts user-defined text), 100, 500, 1000	Set the number of edges measured for the Rise and Fall Time Mismatch Test.
Configure	Rise and Fall Time Mismatch Lane+ Fall Lane- Rise Location (D10.2)	RiseFallTimeMismatchFallRiseLocationD10_2	(Accepts user-defined text), 1	Set the zero based pattern bit location used for D10.2 Lane+ fall time and Lane- rise time measurement in Rise and Fall Time Mismatch Test.
Configure	Rise and Fall Time Mismatch Lane+ Fall Lane- Rise Pattern (D10.2)	RiseFallTimeMismatchFallRisePatternD10_2	(Accepts user-defined text), 10	Set the triggering pattern used for D10.2 Lane+ fall time and Lane- rise time measurement in Rise and Fall Time Mismatch Test.
Configure	Rise and Fall Time Mismatch Lane+ Rise Lane- Fall Location (D10.2)	RiseFallTimeMismatchRiseFallLocationD10_2	(Accepts user-defined text), 1	Set the zero based pattern bit location used for D10.2 Lane+ rise time and Lane- fall time measurement in Rise and Fall Time Mismatch Test.
Configure	Rise and Fall Time Mismatch Lane+ Rise Lane- Fall Pattern (D10.2)	RiseFallTimeMismatchRiseFallPatternD10_2	(Accepts user-defined text), 01	Set the triggering pattern used for D10.2 Lane+ rise time and Lane- fall time measurement in Rise and Fall Time Mismatch Test.
Configure	Rise and Fall Time Mismatch Memory Depth (kpts)	RiseFallTimeMismatchMemoryDepth	(Accepts user-defined text), 100, 500, 1000	Set the memory depth for each acquisition in Rise and Fall Time Mismatch Test. Unit: kpts.
Configure	Rise and Fall Time Mismatch Threshold Level	RiseFallTimeMismatchThresholdLevel	90/10, 85/15, 80/20, 75/25, 70/30	Select the threshold level used for the Rise and Fall Time Mismatch Test. Unit: %.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Rise and Fall Time Mismatch VH Location (D10.2)	RiseFallTimeMismatchVHLocationD10_2	(Accepts user-defined text), 1.5, 1.5	Set the pattern bit location used for D10.2 VH transition measurement in Rise and Fall Time Mismatch Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Rise and Fall Time Mismatch VH Pattern (D10.2)	RiseFallTimeMismatchVHPatternD10_2	(Accepts user-defined text), 01	Set the triggering pattern used for D10.2 VH measurement in Rise and Fall Time Mismatch Test.
Configure	Rise and Fall Time Mismatch VL Location (D10.2)	RiseFallTimeMismatchVLLocationD10_2	(Accepts user-defined text), 1.5, 1.5	Set the pattern bit location used for D10.2 VL transition measurement in Rise and Fall Time Mismatch Test. Use comma separated location value, such as [x,y]. Where x is the start location, y is the end location.
Configure	Rise and Fall Time Mismatch VL Pattern (D10.2)	RiseFallTimeMismatchVLPatternD10_2	(Accepts user-defined text), 10	Set the triggering pattern used for D10.2 VL measurement in Rise and Fall Time Mismatch Test.
Configure	SCPI Command Timeout	SCPITimeout	(Accepts user-defined text), 80000, 160000	Set the timeout period for SCPI command sent to oscilloscope in miliseconds. Unit: ms.
Configure	SSC Cycle Count	SSCCycleCount	(Accepts user-defined text), 10, 20	Set the number of SSC cycle captured and used for SSC related tests. Max number is 25.
Configure	SSC Filter Frequency (MHz)	SSCFilterFrequency	(Accepts user-defined text), 1.98, 1.70	Set the cutoff fequency of the low pass filter used for SSC related tests. Unit: MHz. This configuration only applicable when the [SSC Filter Type] config variable is set to [Second Order Butterwoth Filter].
Configure	SSC Filter Type	SSCFilterType	SecondOrderButterworthFilter, SmoothingFilter	Select the type of the low pass filter used for SSC related tests.
Configure	SSC Smoothing Points - HBR	SSCSmoothingPointsHBR	(Accepts user-defined text), 61, 603, 701	Set the number of smoothing points of the low pass filter used for SSC related tests for HBR. This configuration only applicable when the [SSC Filter Type] config variable is set to [Smoothing Filter].

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	SSC Smoothing Points - HBR2	SSCSmoothing PointsHBR2	(Accepts user-defined text), 120, 1206, 1402	Set the number of smoothing points of the low pass filter used for SSC related tests for HBR2. This configuration only applicable when the [SSC Filter Type] config variable is set to [Smoothing Filter].
Configure	SSC Smoothing Points - HBR3	SSCSmoothing PointsHBR3	(Accepts user-defined text), 120, 1206, 1402	Set the number of smoothing points of the low pass filter used for SSC related tests for HBR3. This configuration only applicable when the [SSC Filter Type] config variable is set to [Smoothing Filter].
Configure	SSC Smoothing Points - RBR	SSCSmoothing PointsRBR	(Accepts user-defined text), 37, 361, 401	Set the number of smoothing points of the low pass filter used for SSC related tests for RBR. This configuration only applicable when the [SSC Filter Type] config variable is set to [Smoothing Filter].
Configure	Sampling Rate (GSa/s) (AUX Channel Tests)	AUXSamplingR ate	5, 10, 20, 40, 8, 16, 32, 64	Set the acquisition sampling rate of the oscilloscope for AUX Channel Tests. Unit: GSa/s.
Configure	Sampling Rate (MSa/s) (AUX Channel Sensitivity Test)	AUXSensitivity SamplingRate	5, 10, 20, 40, 8, 16, 32, 64	Set the acquisition sampling rate of the oscilloscope for AUX Channel Sensitivity Test. Unit: MSa/s.
Configure	Serial Data Pattern Method	SerialDataPatte rnMethod	1, 2	Set the method to search for serial data pattern for VHigh/VLow measurements. For [Method 1], Serial Data Pattern Qualify is used to search for serial data pattern. For [Method 2], InfiniiScan Generic Serial Trigger is used to search for serial data pattern.
Configure	Sink AUX Channel Traffic Timeout (us)	SinkAUXTimeo ut	(Accepts user-defined text), 300, 400	Set the timeout period where sink need to reply for source AUX command. This configuration only applicable when the [Test Method] configuration variable is set to oscilloscope decode method [Scope Method]. Unit: us.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Configure	Source AUX Channel Traffic Timeout (us)	SourceAUXTimeout	(Accepts user-defined text), 300, 400	Set the timeout period where source need to wait for sink reply before transmitting the next AUX command. This configuration only applicable when the [Test Method] configuration variable is set to oscilloscope decode method [Scope Method]. Unit: us.
Configure	Test Method	AUXSensitivityTestMethod	Scope Method, Reference Device Method	Select the test method used for AUX Channel Sensitivity Test to either through built in test from reference device (Reference Device Method) or oscilloscope decode (Scope Method). If the selected reference device does not support built in test, the oscilloscope decode method will be used.
Configure	Threshold Mode	ThresholdMode	Auto, Top Base, Min Max, Absolute Zero	Select the threshold mode for the measurement either VMax/VMin, VTop/VBase or Absolute Zero.
Configure	Transition Time Edges	TransitionTimeEdge	(Accepts user-defined text), 100, 500, 1000	Set the number of edges measured for Differential Transition Time Test.
Configure	Transition Time Memory Depth (kpts)	TransitionTimeMemoryDepth	(Accepts user-defined text), 100, 500, 1000	Set the memory depth for each acquisition in Differential Transition Time Test. Unit: kpts.
Configure	Transition Time Threshold	TransitionTimeThreshold	90/10, 85/15, 80/20, 75/25, 70/30	Set the threshold for the Differential Transition Time Test. Unit: Percentage.
Configure	VH Pattern	VHPattern	1010111111, 101011111, 10101111	Set the pattern for VH measurement to either 1111110, 11110, 1110 or 110. The default setting is 1111110.
Configure	VL Pattern	VLPattern	1010000, 101000	Set the pattern for VL measurement to either 0000001, 00001, 0001 or 001. The default setting is 0000001.
Configure	VTop VBase Waveform Count	VTopVBaseWaveformCount	(Accepts user-defined text), 20, 50, 100	Set the number of waveforms used when performing the VTop and VBase measurement. Increasing this value increases the test run time but improves the repeatability of the measurement.
Run Tests	Event	RunEvent	(None), Fail, Margin < N, Pass	Names of events that can be used with the StoreMode=Event or RunUntil RunEventAction options

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Run Tests	RunEvent=Margin < N: Minimum required margin %	RunEvent_Margin < N_MinPercent	Any integer in range: 0 <= value <= 99	Specify N using the 'Minimum required margin %' control.
Set Up	AUX Channel Differential Vertical Offset	perTextOffset	(Accepts user-defined text)	Set the vertical offset of AUX Channel differential signal in mV. Set the vertical offset of AUX Channel differential signal in mV.
Set Up	AUX Channel Differential Vertical Scale	perTxtVerticalScale	(Accepts user-defined text)	Set the vertical scale of AUX Channel differential signal in mV. Set the vertical scale of AUX Channel differential signal in mV.
Set Up	AUX Channel Holdoff Time	perTxtHoldOffTime	(Accepts user-defined text)	Set the trigger holdoff time used for signal acquisition of AUX Channel Physical Layer Tests in us. Set the trigger holdoff time used for signal acquisition of AUX Channel Physical Layer Tests in us.
Set Up	AUX Channel Lane	AuxLane	Channel 1, Channel 2, Channel 3, Channel 4	Select the channel used for AUX Channel Lane when using Differential Probe Connection or AUX Plus Lane when using Single-Ended Connection. Select the channel used for AUX Channel Lane when using Differential Probe Connection or AUX Plus Lane when using Single-Ended Connection.
Set Up	AUX Channel Lower Threshold	perTxtAuxLowerThreshold	(Accepts user-defined text)	Set the measurement lower threshold used for AUX Channel Physical Layer Tests in mV. Set the measurement lower threshold used for AUX Channel Physical Layer Tests in mV.
Set Up	AUX Channel Single-Ended Vertical Scale	AUXSEChannelScale	(Accepts user-defined text)	Set the vertical scale of AUX Channel single-ended signal in mV when using Single-Ended Connection. Note: AUX+ and AUX- signal share the same vertical scale. Set the vertical scale of AUX Channel single-ended signal in mV when using Single-Ended Connection. Note: AUX+ and AUX- signal share the same vertical scale.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	AUX Channel Trigger Level	perTxtTriggerLevel	(Accepts user-defined text)	Set the trigger level used for signal acquisition of AUX Channel Physical Layer Tests in mV. Set the trigger level used for signal acquisition of AUX Channel Physical Layer Tests in mV.
Set Up	AUX Channel Upper Threshold	perTxtAuxUpperThreshold	(Accepts user-defined text)	Set the measurement upper threshold used for AUX Channel Physical Layer Tests in mV. Set the measurement upper threshold used for AUX Channel Physical Layer Tests in mV.
Set Up	AUX Minus Channel Lane	AuxMinusLane	Channel 3, Channel 4	Select the channel used for AUX Minus Channel Lane when using Single-Ended Connection. Select the channel used for AUX Minus Channel Lane when using Single-Ended Connection.
Set Up	AUX Minus Channel Probe Offset	ProbeMinusOffset	(Accepts user-defined text)	Set the probe offset in mV of AUX Minus Channel when using Single-Ended Connection. Set the probe offset in mV of AUX Minus Channel when using Single-Ended Connection.
Set Up	AUX Plus Channel Probe Offset	ProbePlusOffset	(Accepts user-defined text)	Set the probe offset in mV of AUX Channel when using Differential Probe Connection or AUX Plus Channel when using Single-Ended Connection. Set the probe offset in mV of AUX Channel when using Differential Probe Connection or AUX Plus Channel when using Single-Ended Connection.
Set Up	Acquisition Mode (AUX Channel Physical Layer Tests)	AuxChannelAcquisitionMode	Live, Offline	Select the mode used for signal acquisition of AUX Channel Physical Layer Tests. Select the mode used for signal acquisition of AUX Channel Physical Layer Tests.
Set Up	Bit Rate 1	Bit Rate 1	0.0, 1.0	Enable or disable Bit Rate 1 support. Enable or disable Bit Rate 1 support.
Set Up	Bit Rate 2	Bit Rate 2	0.0, 1.0	Enable or disable Bit Rate 2 support. Enable or disable Bit Rate 2 support.
Set Up	Bit Rate 3	Bit Rate 3	0.0, 1.0	Enable or disable Bit Rate 3 support. Enable or disable Bit Rate 3 support.
Set Up	Bit Rate 4	Bit Rate 4	0.0, 1.0	Enable or disable Bit Rate 4 support. Enable or disable Bit Rate 4 support.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Comments	Comments	(Accepts user-defined text)	Additional comments. Additional comments.
Set Up	Connection Setup Complete Status	ConnectionSetupComplete	0.0, 1.0	Determine whether the connection setup is completed. Determine whether the connection setup is completed.
Set Up	Connection Type (AUX Channel Physical Layer Tests)	AUXConnectionType	Differential Probe, Single-Ended (A-B)	Select the connection type, either 'Differential Probe' connection or 'Single-Ended (A-B)' connection for AUX Channel Physical Layer Tests. Select the connection type, either 'Differential Probe' connection or 'Single-Ended (A-B)' connection for AUX Channel Physical Layer Tests.
Set Up	Connection Type (Physical Layer Tests)	ConnectionType	Differential Probe, Single-Ended (A-B)	Select the connection type, either 'Differential Probe' connection or 'Single-Ended (A-B)' connection for Physical Layer Tests. If 'Single-Ended Tests' or 'Both' is selected for 'Test Type', only 'Single-Ended (A-B)' connection will be available. Select the connection type, either 'Differential Probe' connection or 'Single-Ended (A-B)' connection for Physical Layer Tests. If 'Single-Ended Tests' or 'Both' is selected for 'Test Type', only 'Single-Ended (A-B)' connection will be available.
Set Up	De-Embed Fixture	DeEmbedFixture	0.0, 1.0	Enable or disable fixture de-embedding based on the 'Fixture Type' selected. Enable or disable fixture de-embedding based on the 'Fixture Type' selected.
Set Up	Device Definition File Path	DeviceDefinitionFilePath	(Accepts user-defined text)	Set the file path for Device Definition file to be loaded. Set the file path for Device Definition file to be loaded.
Set Up	Device Definition Setup Complete Status	DeviceDefinitionSetupComplete	0.0, 1.0	Determine whether the device definition setup is completed. Determine whether the device definition setup is completed.
Set Up	Device ID	DeviceID	(Accepts user-defined text)	Device identifier. Device identifier.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Device Type (AUX Channel Physical Layer Tests)	AUXDUTType	Source, Sink	Select the device type,'Source', 'Sink' for AUX Channel Physical Layer Tests. The 'Sink' is currently not supported. Select the device type,'Source', 'Sink' for AUX Channel Physical Layer Tests. The 'Sink' is currently not supported.
Set Up	Device Type (Physical Layer Tests)	DeviceType	Source, Sink, Cable	Select the device type, either 'Source', 'Sink' or 'Cable' for Physical Layer Tests. Select the device type, either 'Source', 'Sink' or 'Cable' for Physical Layer Tests.
Set Up	Enable Test Controller Automation	pcbEnableAutomation	0.0, 1.0	Enable or disable Test Controller automation. Enable or disable Test Controller automation.
Set Up	Fixture Type (Physical Layer Tests)	FixtureType	Wilder Tech eDP-TPA30, Wilder Tech eDP-TPA40, Wilder Tech eDP-TPA50, Custom, None	Select the fixture type based on the actual fixture used for Physical Layer Tests. If the actual fixture used is not listed, please select 'Custom'. Select the fixture type based on the actual fixture used for Physical Layer Tests. If the actual fixture used is not listed, please select 'Custom'.
Set Up	Lane	Lane	1 Lane, 2 Lanes, 4 Lanes	Select the number of lane(s) supported by the DUT. Select the number of lane(s) supported by the DUT.
Set Up	Lane 0 (Differential Probe)	Lane0	Channel 1, Channel 2, Channel 3, Channel 4	Select the channel used for Lane 0 when using Differential Probe Connection. Select the channel used for Lane 0 when using Differential Probe Connection.
Set Up	Lane 0 Minus (Single Ended)	Lane0Minus	Channel 3, Channel 4	Select the channel used for Lane 0- when using Single-Ended Connection. Select the channel used for Lane 0- when using Single-Ended Connection.
Set Up	Lane 0 Plus (Single Ended)	Lane0Plus	Channel 1, Channel 2	Select the channel used for Lane 0+ when using Single-Ended Connection. Select the channel used for Lane 0+ when using Single-Ended Connection.
Set Up	Lane 1 (Differential Probe)	Lane1	Channel 1, Channel 2, Channel 3, Channel 4	Select the channel used for Lane 1 when using Differential Probe Connection. Select the channel used for Lane 1 when using Differential Probe Connection.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Lane 1 Minus (Single Ended)	Lane1Minus	Channel 3, Channel 4	Select the channel used for Lane 1- when using Single-Ended Connection. Select the channel used for Lane 1- when using Single-Ended Connection.
Set Up	Lane 1 Plus (Single Ended)	Lane1Plus	Channel 1, Channel 2	Select the channel used for Lane 1+ when using Single-Ended Connection. Select the channel used for Lane 1+ when using Single-Ended Connection.
Set Up	Lane 2 (Differential Probe)	Lane2	Channel 1, Channel 2, Channel 3, Channel 4	Select the channel used for Lane 2 when using Differential Probe Connection. Select the channel used for Lane 2 when using Differential Probe Connection.
Set Up	Lane 2 Minus (Single Ended)	Lane2Minus	Channel 3, Channel 4	Select the channel used for Lane 2- when using Single-Ended Connection. Select the channel used for Lane 2- when using Single-Ended Connection.
Set Up	Lane 2 Plus (Single Ended)	Lane2Plus	Channel 1, Channel 2	Select the channel used for Lane 2+ when using Single-Ended Connection. Select the channel used for Lane 2+ when using Single-Ended Connection.
Set Up	Lane 3 (Differential Probe)	Lane3	Channel 1, Channel 2, Channel 3, Channel 4	Select the channel used for Lane 3 when using Differential Probe Connection. Select the channel used for Lane 3 when using Differential Probe Connection.
Set Up	Lane 3 Minus (Single Ended)	Lane3Minus	Channel 3, Channel 4	Select the channel used for Lane 3- when using Single-Ended Connection. Select the channel used for Lane 3- when using Single-Ended Connection.
Set Up	Lane 3 Plus (Single Ended)	Lane3Plus	Channel 1, Channel 2	Select the channel used for Lane 3+ when using Single-Ended Connection. Select the channel used for Lane 3+ when using Single-Ended Connection.
Set Up	Lane A (2 Lanes and 4 Lanes, Differential Probe, Physical Layer Tests)	LaneA	Lane 0	Select the first lane (Lane A) if number of channels is less than number of lanes when using Differential Probe Connection. Select the first lane (Lane A) if number of channels is less than number of lanes when using Differential Probe Connection.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Lane A (2 Lanes and 4 Lanes, Single-Ended, Physical Layer Tests)	LaneASMA	Lane 0	Select the first lane (Lane A) if number of channels is less than number of lanes when using Single-Ended Connection. Select the first lane (Lane A) if number of channels is less than number of lanes when using Single-Ended Connection.
Set Up	Lane B (4 Lanes, Differential Probe, Physical Layer Tests)	LaneB	Lane 0	Select the second lane (Lane B) if number of channels is less than number of lanes when using Differential Probe Connection. Select the second lane (Lane B) if number of channels is less than number of lanes when using Differential Probe Connection.
Set Up	Lane B (4 Lanes, Single-Ended, Physical Layer Tests)	LaneBSMA	Lane 0	Select the second lane (Lane B) if number of channels is less than number of lanes when using Single-Ended Connection. Select the second lane (Lane B) if number of channels is less than number of lanes when using Single-Ended Connection.
Set Up	No of Channels (Physical Layer Tests)	ConnectionSetting	1 Channel	Select the number of channel(s) based on the actual number of channel(s) used for Physical Layer Tests. Select the number of channel(s) based on the actual number of channel(s) used for Physical Layer Tests.
Set Up	Number of Save Waveform (AUX Channel Physical Layer Tests)	perTxtAcquisitionNo	(Accepts user-defined text)	Set the number of waveform to be saved for offline processing of AUX Channel Physical Layer Tests. Set the number of waveform to be saved for offline processing of AUX Channel Physical Layer Tests.
Set Up	Operator ID	OperatorID	(Accepts user-defined text)	Operator identifier. Operator identifier.
Set Up	Post-Cursor 2 Level 0	Level 0	0.0, 1.0	Enable or disable Post-Cursor 2 Level 0 support. Enable or disable Post-Cursor 2 Level 0 support.
Set Up	Post-Cursor 2 Level 1	Level 1	0.0, 1.0	Enable or disable Post-Cursor 2 Level 1 support. Enable or disable Post-Cursor 2 Level 1 support.
Set Up	Post-Cursor 2 Level 2	Level 2	0.0, 1.0	Enable or disable Post-Cursor 2 Level 2 support. Enable or disable Post-Cursor 2 Level 2 support.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Post-Cursor 2 Level 3	Level 3	0.0, 1.0	Enable or disable Post-Cursor 2 Level 3 support. Enable or disable Post-Cursor 2 Level 3 support.
Set Up	Pre-emphasis 0	Pre-emphasis 0	0.0, 1.0	Enable or disable Pre-emphasis Level 0 support. Enable or disable Pre-emphasis Level 0 support.
Set Up	Pre-emphasis 1	Pre-emphasis 1	0.0, 1.0	Enable or disable Pre-emphasis Level 1 support. Enable or disable Pre-emphasis Level 1 support.
Set Up	Pre-emphasis 2	Pre-emphasis 2	0.0, 1.0	Enable or disable Pre-emphasis Level 2 support. Enable or disable Pre-emphasis Level 2 support.
Set Up	Pre-emphasis 3	Pre-emphasis 3	0.0, 1.0	Enable or disable Pre-emphasis Level 3 support. Enable or disable Pre-emphasis Level 3 support.
Set Up	Project ID	ProjectID	(Accepts user-defined text)	Project identifier. Project identifier.
Set Up	Reference Device (AUX Channel Physical Layer Tests)	ReferenceDUT Connectivity	Yes, No	Select whether a reference source or sink is connected for AUX Channel Physical Layer Tests. Select whether a reference source or sink is connected for AUX Channel Physical Layer Tests.
Set Up	SSC Disabled	SSC Disabled	0.0, 1.0	Enable or disable SSC Disabled support. Enable or disable SSC Disabled support.
Set Up	SSC Enabled	SSC Enabled	0.0, 1.0	Enable or disable SSC Enabled support. Enable or disable SSC Enabled support.
Set Up	Save Waveform Type (AUX Channel Physical Layer Tests)	AUXWaveformType	AUX Channel Tests, AUX Channel Calibration Tests, AUX Channel Sensitivity Tests	Select the type of waveform to be saved for AUX Channel Physical Layer Tests. Select the type of waveform to be saved for AUX Channel Physical Layer Tests.
Set Up	Show Normative Tests Only	HideInformative	0.0, 1.0	Enable or disable show normative tests only. Enable or disable show normative tests only.
Set Up	Test Controller	AutomatedType	AUXAUX1, JBERTASimulation, JBERTBSimulation, PulseGenSim, TCPIP, UnigrafDPTC	Select the Test Controller used for automation. Select the Test Controller used for automation.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Test Controller Configuration	AutomationConfig	(Accepts user-defined text)	Configure the Test Controller remotely. Note: The Test Controller must be enabled before configure the Test Controller remotely. Configure the Test Controller remotely. Note: The Test Controller must be enabled before configure the Test Controller remotely.
Set Up	Test Controller Script File	perTxtScript	(Accepts user-defined text)	Select the script file for Test Controller automation. This script file only applicable if script mode is enabled. Select the script file for Test Controller automation. This script file only applicable if script mode is enabled.
Set Up	Test Selection	TestSelection	Physical Layer Tests, AUX Channel Physical Layer Tests	Select the test selection. Select the test selection.
Set Up	Test Setup Complete Status	TestSetupComplete	0.0, 1.0	Determine whether the test setup is completed. Determine whether the test setup is completed.
Set Up	Test Specification	DPCTSVersion	eDP 1.4b, eDP 1.5	Select the test specification. Select the test specification.
Set Up	Test Type (Physical Layer Tests)	TestType	Differential Tests, Single-Ended Tests, Both	Select the test type, either 'Differential Tests', 'Single-Ended Tests' or 'Both' for Physical Layer Tests if 'Source' is selected for 'Device Type'. Note: For 'Both', both differential tests and single-ended tests will be available with single-ended connection. Select the test type, either 'Differential Tests', 'Single-Ended Tests' or 'Both' for Physical Layer Tests if 'Source' is selected for 'Device Type'. Note: For 'Both', both differential tests and single-ended tests will be available with single-ended connection.
Set Up	Voltage Level Swing 0	Swing 0	0.0, 1.0	Enable or disable Voltage Level Swing 0 support. Enable or disable Voltage Level Swing 0 support.
Set Up	Voltage Level Swing 1	Swing 1	0.0, 1.0	Enable or disable Voltage Level Swing 1 support. Enable or disable Voltage Level Swing 1 support.

Table 2   Configuration Variables and Values (continued)

GUI Location	Label	Variable	Values	Description
Set Up	Voltage Level Swing 2	Swing 2	0.0, 1.0	Enable or disable Voltage Level Swing 2 support. Enable or disable Voltage Level Swing 2 support.
Set Up	Voltage Level Swing 3	Swing 3	0.0, 1.0	Enable or disable Voltage Level Swing 3 support. Enable or disable Voltage Level Swing 3 support.

3 Test Names and IDs

The following table shows the mapping between each test's numeric ID and name. The numeric ID is required by various remote interface methods.

· Name — The name of the test as it appears on the user interface **Select Tests** tab.

· Test ID — The number to use with the RunTests method.

· Description — The description of the test as it appears on the user interface **Select Tests** tab.

For example, if the graphical user interface displays this tree in the **Select Tests** tab:

· All Tests

   · Rise Time

   · Fall Time

then you would expect to see something like this in the table below:

Table 3   Example Test Names and IDs

Name	Test ID	Description
Fall Time	110	Measures clock fall time.
Rise Time	100	Measures clock rise time.

and you would run these tests remotely using:

```
ARSL syntax
-----------
arsl -a ipaddress -c "SelectedTests '100,110'"
arsl -a ipaddress -c "Run"

C# syntax
---------
remoteAte.SelectedTests = new int[]{100,110};
remoteAte.Run();
```

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Here are the actual Test names and IDs used by this application. Listed at the end, you may also find:

· Deprecated IDs and their replacements.

· Macro IDs which may be used to select multiple related tests at the same time.

| NOTE | The file, "TestInfo.txt", which may be found in the same directory as this help file, contains all of the information found in the table below in a format suitable for parsing. |

Table 4   Test IDs and Names

Name	TestID	Description
10.1 Aux Channel Eye Test (Sink)	1111212	To evaluate the AUX Channel waveform for sink device ensuring that timing variables and amplitude trajectories support DisplayPort system objectives of Bit Error Rate in data transmission.
10.1 Aux Channel Eye Test (Source)	1111202	To evaluate the AUX Channel waveform for source device ensuring that timing variables and amplitude trajectories support DisplayPort system objectives of Bit Error Rate in data transmission.
10.1 Aux Channel Peak to Peak Voltage Test (Sink)	1111213	To evaluate the peak to peak voltage AUX Channel waveform for sink.
10.1 Aux Channel Peak to Peak Voltage Test (Source)	1111203	To evaluate the peak to peak voltage AUX Channel waveform for source.
10.2 Aux Channel Eye Sensitivity Test (Sink)	1113211	To evaluate the sensitivity to the AUX Channel eye opening of a Device Under Test.
10.2 Aux Channel Eye Sensitivity Test (Source)	1113201	To evaluate the sensitivity to the AUX Channel eye opening of a Device Under Test.
Aux Channel Eye Sensitivity Calibration (Reference Sink)	1112201	The test is for calibration purpose to help adjusting AUX eye opening to suitable level. The test validates if voltage swing of a reference Sink AUX eye opening has meet the minimum level for futher AUX sensitivity testing.
Aux Channel Eye Sensitivity Calibration (Reference Source)	1112211	The test is for calibration purpose to help adjusting AUX eye opening to suitable level. The test validates if voltage swing of a reference Source AUX eye opening has meet the minimum level for futher AUX sensitivity testing.
Aux Channel Unit Interval Test (Sink)	1111211	To evaluate the unit interval of AUX Channel.
Aux Channel Unit Interval Test (Source)	1111201	To evaluate the unit interval of AUX Channel.
Clock Recovery Configuration Settings	1201	
Equalizer Configuration Settings	1202	
Eye Diagram Configuration Settings	1203	
General Configuration Settings	1200	

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Jitter Configuration Settings	1204	
Lane 0 - AC Common Mode Noise Test (HBR2CPAT)	510201	To report common mode noise (unfiltered RMS) of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 0 - AC Common Mode Noise Test (TPS4)	515201	To report common mode noise (unfiltered RMS) of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Deterministic Jitter Test (D10.2)	43201	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Deterministic Jitter Test (HBR2CPAT)	40201	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Deterministic Jitter Test (Other Pattern)	49201	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Deterministic Jitter Test (PRBS 7)	41201	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Deterministic Jitter Test (PRBS 9)	42201	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Deterministic Jitter Test (Random Pattern)	48201	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Deterministic Jitter Test (TPS4)	45201	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Differential Voltage Level Test (HBR2CPAT)	70201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (HBR2CPAT)	80201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (Other Pattern)	79201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 0 - Differential Voltage Level Test (Other Pattern)	89201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (PLTPAT)	74201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (PLTPAT)	84201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (PRBS 7)	71201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (PRBS 7)	81201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (PRBS 9)	72201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (PRBS 9)	82201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (Random Pattern)	78201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (Random Pattern)	88201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (TPS4)	75201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Differential Voltage Level Test (TPS4)	85201	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Eye Diagram Test (D10.2)	13201	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 0 - Eye Diagram Test (HBR2CPAT)	10201	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 0 - Eye Diagram Test (Other Pattern)	19201	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 0 - Eye Diagram Test (PRBS 7)	11201	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 0 - Eye Diagram Test (PRBS 9)	12201	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 0 - Eye Diagram Test (Random Pattern)	18201	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 0 - Eye Diagram Test (TPS4)	15201	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 0 - Fall Time Test (D10.2)	123201	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Fall Time Test (HBR2CPAT)	120201	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Fall Time Test (Other Pattern)	129201	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Fall Time Test (PLTPAT)	124201	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Fall Time Test (PRBS 7)	121201	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Fall Time Test (PRBS 9)	122201	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Fall Time Test (Random Pattern)	128201	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Fall Time Test (TPS4)	125201	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Intra Pair Skew Test (D10.2)	503201	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Intra Pair Skew Test (HBR2CPAT)	500201	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Intra Pair Skew Test (TPS4)	505201	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 0 - Main Link Frequency Compliance Test (D10.2)	203201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (D10.2)	253201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (HBR2CPAT)	200201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (HBR2CPAT)	250201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (Other Pattern)	209201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (Other Pattern)	259201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (PRBS 7)	201201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (PRBS 7)	251201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (PRBS 9)	202201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (PRBS 9)	252201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (Random Pattern)	208201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (Random Pattern)	258201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (TPS4)	205201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Main Link Frequency Compliance Test (TPS4)	255201	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 0 - Non ISI Jitter Test (D10.2)	23201	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 0 - Non ISI Jitter Test (HBR2CPAT)	20201	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 0 - Non ISI Jitter Test (Other Pattern)	29201	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 0 - Non ISI Jitter Test (PRBS 7)	21201	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 0 - Non ISI Jitter Test (PRBS 9)	22201	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Lane 0 - Non ISI Jitter Test (Random Pattern)	28201	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 0 - Non ISI Jitter Test (TPS4)	25201	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 0 - Peak to Peak Differential Voltage Test (HBR2CPAT)	60201	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Peak to Peak Differential Voltage Test (Other Pattern)	69201	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Peak to Peak Differential Voltage Test (PLTPAT)	64201	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Peak to Peak Differential Voltage Test (PRBS 7)	61201	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Peak to Peak Differential Voltage Test (PRBS 9)	62201	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Peak to Peak Differential Voltage Test (Random Pattern)	68201	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Peak to Peak Differential Voltage Test (TPS4)	65201	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (HBR2CPAT)	90201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (HBR2CPAT)	100201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (Other Pattern)	99201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (Other Pattern)	109201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (PLTPAT)	94201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (PLTPAT)	104201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (PRBS 7)	91201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (PRBS 7)	101201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (PRBS 9)	92201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (PRBS 9)	102201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 0 - Pre-Emphasis Level Test (Random Pattern)	98201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (Random Pattern)	108201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (TPS4)	95201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Pre-Emphasis Level Test (TPS4)	105201	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 0 - Random Jitter Test (D10.2)	53201	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Random Jitter Test (HBR2CPAT)	50201	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Random Jitter Test (Other Pattern)	59201	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Random Jitter Test (PRBS 7)	51201	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Random Jitter Test (PRBS 9)	52201	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Random Jitter Test (Random Pattern)	58201	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Random Jitter Test (TPS4)	55201	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Rise Time Test (D10.2)	113201	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.

Table 4 Test IDs and Names (continued)

Name	TestID	Description
Lane 0 - Rise Time Test (HBR2CPAT)	110201	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Rise Time Test (Other Pattern)	119201	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Rise Time Test (PLTPAT)	114201	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Rise Time Test (PRBS 7)	111201	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Rise Time Test (PRBS 9)	112201	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Rise Time Test (Random Pattern)	118201	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - Rise Time Test (TPS4)	115201	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 0 - SSC Modulation Deviation Test (D10.2)	353201	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 0 - SSC Modulation Deviation Test (HBR2CPAT)	350201	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 0 - SSC Modulation Deviation Test (Other Pattern)	359201	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 0 - SSC Modulation Deviation Test (PRBS 7)	351201	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 0 - SSC Modulation Deviation Test (PRBS 9)	352201	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 0 - SSC Modulation Deviation Test (Random Pattern)	358201	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 0 - SSC Modulation Deviation Test (TPS4)	355201	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 0 - SSC Modulation Frequency Test (D10.2)	303201	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 0 - SSC Modulation Frequency Test (HBR2CPAT)	300201	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 0 - SSC Modulation Frequency Test (Other Pattern)	309201	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 0 - SSC Modulation Frequency Test (PRBS 7)	301201	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 0 - SSC Modulation Frequency Test (PRBS 9)	302201	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 0 - SSC Modulation Frequency Test (Random Pattern)	308201	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 0 - SSC Modulation Frequency Test (TPS4)	305201	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 0 - Single-Ended Rise and Fall Time Mismatch Test (D10.2)	523201	To evaluate the difference in rise and fall times of the two single-ended signals in a given differential data lane of the eDP interface.
Lane 0 - Total Jitter Test (D10.2)	33201	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Total Jitter Test (HBR2CPAT)	30201	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Total Jitter Test (Other Pattern)	39201	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Total Jitter Test (PRBS 7)	31201	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Total Jitter Test (PRBS 9)	32201	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Total Jitter Test (Random Pattern)	38201	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 0 - Total Jitter Test (TPS4)	35201	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 0 / Lane 1 - Inter Pair Skew Test (HBR2CPAT)	130201	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 1 - Inter Pair Skew Test (Other Pattern)	139201	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 1 - Inter Pair Skew Test (PRBS 7)	131201	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 1 - Inter Pair Skew Test (PRBS 9)	132201	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 1 - Inter Pair Skew Test (Random Pattern)	138201	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 1 - Inter Pair Skew Test (TPS4)	135201	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 2 - Inter Pair Skew Test (HBR2CPAT)	130202	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 2 - Inter Pair Skew Test (Other Pattern)	139202	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 2 - Inter Pair Skew Test (PRBS 7)	131202	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 2 - Inter Pair Skew Test (PRBS 9)	132202	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 2 - Inter Pair Skew Test (Random Pattern)	138202	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 2 - Inter Pair Skew Test (TPS4)	135202	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 3 - Inter Pair Skew Test (HBR2CPAT)	130203	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 3 - Inter Pair Skew Test (Other Pattern)	139203	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 3 - Inter Pair Skew Test (PRBS 7)	131203	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 3 - Inter Pair Skew Test (PRBS 9)	132203	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 3 - Inter Pair Skew Test (Random Pattern)	138203	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 0 / Lane 3 - Inter Pair Skew Test (TPS4)	135203	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 1 - AC Common Mode Noise Test (HBR2CPAT)	510202	To report common mode noise (unfiltered RMS) of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 1 - AC Common Mode Noise Test (TPS4)	515202	To report common mode noise (unfiltered RMS) of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Deterministic Jitter Test (D10.2)	43202	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Deterministic Jitter Test (HBR2CPAT)	40202	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Deterministic Jitter Test (Other Pattern)	49202	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Deterministic Jitter Test (PRBS 7)	41202	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Deterministic Jitter Test (PRBS 9)	42202	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Deterministic Jitter Test (Random Pattern)	48202	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Deterministic Jitter Test (TPS4)	45202	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Differential Voltage Level Test (HBR2CPAT)	70202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (HBR2CPAT)	80202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (Other Pattern)	79202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 1 - Differential Voltage Level Test (Other Pattern)	89202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (PLTPAT)	74202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (PLTPAT)	84202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (PRBS 7)	71202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (PRBS 7)	81202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (PRBS 9)	72202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (PRBS 9)	82202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (Random Pattern)	78202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (Random Pattern)	88202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (TPS4)	75202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Differential Voltage Level Test (TPS4)	85202	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Eye Diagram Test (D10.2)	13202	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 1 - Eye Diagram Test (HBR2CPAT)	10202	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 1 - Eye Diagram Test (Other Pattern)	19202	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 1 - Eye Diagram Test (PRBS 7)	11202	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 1 - Eye Diagram Test (PRBS 9)	12202	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 1 - Eye Diagram Test (Random Pattern)	18202	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 1 - Eye Diagram Test (TPS4)	15202	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 1 - Fall Time Test (D10.2)	123202	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Fall Time Test (HBR2CPAT)	120202	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Fall Time Test (Other Pattern)	129202	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Fall Time Test (PLTPAT)	124202	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Fall Time Test (PRBS 7)	121202	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Fall Time Test (PRBS 9)	122202	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Fall Time Test (Random Pattern)	128202	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Fall Time Test (TPS4)	125202	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Intra Pair Skew Test (D10.2)	503202	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Intra Pair Skew Test (HBR2CPAT)	500202	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Intra Pair Skew Test (TPS4)	505202	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 1 - Main Link Frequency Compliance Test (D10.2)	203202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (D10.2)	253202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (HBR2CPAT)	200202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (HBR2CPAT)	250202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (Other Pattern)	209202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (Other Pattern)	259202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (PRBS 7)	201202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (PRBS 7)	251202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (PRBS 9)	202202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (PRBS 9)	252202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (Random Pattern)	208202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (Random Pattern)	258202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (TPS4)	205202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Main Link Frequency Compliance Test (TPS4)	255202	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 1 - Non ISI Jitter Test (D10.2)	23202	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 1 - Non ISI Jitter Test (HBR2CPAT)	20202	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 1 - Non ISI Jitter Test (Other Pattern)	29202	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 1 - Non ISI Jitter Test (PRBS 7)	21202	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 1 - Non ISI Jitter Test (PRBS 9)	22202	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 1 - Non ISI Jitter Test (Random Pattern)	28202	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 1 - Non ISI Jitter Test (TPS4)	25202	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 1 - Peak to Peak Differential Voltage Test (HBR2CPAT)	60202	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Peak to Peak Differential Voltage Test (Other Pattern)	69202	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Peak to Peak Differential Voltage Test (PLTPAT)	64202	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Peak to Peak Differential Voltage Test (PRBS 7)	61202	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Peak to Peak Differential Voltage Test (PRBS 9)	62202	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Peak to Peak Differential Voltage Test (Random Pattern)	68202	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Peak to Peak Differential Voltage Test (TPS4)	65202	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (HBR2CPAT)	90202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (HBR2CPAT)	100202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (Other Pattern)	99202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (Other Pattern)	109202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (PLTPAT)	94202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (PLTPAT)	104202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (PRBS 7)	91202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (PRBS 7)	101202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (PRBS 9)	92202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (PRBS 9)	102202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 1 - Pre-Emphasis Level Test (Random Pattern)	98202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (Random Pattern)	108202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (TPS4)	95202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Pre-Emphasis Level Test (TPS4)	105202	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 1 - Random Jitter Test (D10.2)	53202	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Random Jitter Test (HBR2CPAT)	50202	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Random Jitter Test (Other Pattern)	59202	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Random Jitter Test (PRBS 7)	51202	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Random Jitter Test (PRBS 9)	52202	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Random Jitter Test (Random Pattern)	58202	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Random Jitter Test (TPS4)	55202	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Rise Time Test (D10.2)	113202	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 1 - Rise Time Test (HBR2CPAT)	110202	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Rise Time Test (Other Pattern)	119202	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Rise Time Test (PLTPAT)	114202	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Rise Time Test (PRBS 7)	111202	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Rise Time Test (PRBS 9)	112202	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Rise Time Test (Random Pattern)	118202	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - Rise Time Test (TPS4)	115202	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 1 - SSC Modulation Deviation Test (D10.2)	353202	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 1 - SSC Modulation Deviation Test (HBR2CPAT)	350202	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 1 - SSC Modulation Deviation Test (Other Pattern)	359202	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 1 - SSC Modulation Deviation Test (PRBS 7)	351202	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 1 - SSC Modulation Deviation Test (PRBS 9)	352202	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 1 - SSC Modulation Deviation Test (Random Pattern)	358202	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 1 - SSC Modulation Deviation Test (TPS4)	355202	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 1 - SSC Modulation Frequency Test (D10.2)	303202	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 1 - SSC Modulation Frequency Test (HBR2CPAT)	300202	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 1 - SSC Modulation Frequency Test (Other Pattern)	309202	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 1 - SSC Modulation Frequency Test (PRBS 7)	301202	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 1 - SSC Modulation Frequency Test (PRBS 9)	302202	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 1 - SSC Modulation Frequency Test (Random Pattern)	308202	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 1 - SSC Modulation Frequency Test (TPS4)	305202	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 1 - Single-Ended Rise and Fall Time Mismatch Test (D10.2)	523202	To evaluate the difference in rise and fall times of the two single-ended signals in a given differential data lane of the eDP interface.
Lane 1 - Total Jitter Test (D10.2)	33202	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Total Jitter Test (HBR2CPAT)	30202	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Total Jitter Test (Other Pattern)	39202	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Total Jitter Test (PRBS 7)	31202	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Total Jitter Test (PRBS 9)	32202	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Total Jitter Test (Random Pattern)	38202	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 1 - Total Jitter Test (TPS4)	35202	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 1 / Lane 2 - Inter Pair Skew Test (HBR2CPAT)	130204	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 2 - Inter Pair Skew Test (Other Pattern)	139204	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 2 - Inter Pair Skew Test (PRBS 7)	131204	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 2 - Inter Pair Skew Test (PRBS 9)	132204	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 2 - Inter Pair Skew Test (Random Pattern)	138204	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 2 - Inter Pair Skew Test (TPS4)	135204	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 3 - Inter Pair Skew Test (HBR2CPAT)	130205	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 3 - Inter Pair Skew Test (Other Pattern)	139205	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 3 - Inter Pair Skew Test (PRBS 7)	131205	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 3 - Inter Pair Skew Test (PRBS 9)	132205	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 3 - Inter Pair Skew Test (Random Pattern)	138205	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 1 / Lane 3 - Inter Pair Skew Test (TPS4)	135205	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 2 - AC Common Mode Noise Test (HBR2CPAT)	510203	To report common mode noise (unfiltered RMS) of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 2 - AC Common Mode Noise Test (TPS4)	515203	To report common mode noise (unfiltered RMS) of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Deterministic Jitter Test (D10.2)	43203	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Deterministic Jitter Test (HBR2CPAT)	40203	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 2 - Deterministic Jitter Test (Other Pattern)	49203	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Deterministic Jitter Test (PRBS 7)	41203	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Deterministic Jitter Test (PRBS 9)	42203	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Deterministic Jitter Test (Random Pattern)	48203	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Deterministic Jitter Test (TPS4)	45203	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Differential Voltage Level Test (HBR2CPAT)	70203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (HBR2CPAT)	80203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (Other Pattern)	79203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (Other Pattern)	89203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (PLTPAT)	74203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (PLTPAT)	84203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (PRBS 7)	71203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (PRBS 7)	81203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (PRBS 9)	72203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (PRBS 9)	82203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 2 - Differential Voltage Level Test (Random Pattern)	78203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (Random Pattern)	88203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (TPS4)	75203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Differential Voltage Level Test (TPS4)	85203	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Eye Diagram Test (D10.2)	13203	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 2 - Eye Diagram Test (HBR2CPAT)	10203	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 2 - Eye Diagram Test (Other Pattern)	19203	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 2 - Eye Diagram Test (PRBS 7)	11203	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 2 - Eye Diagram Test (PRBS 9)	12203	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 2 - Eye Diagram Test (Random Pattern)	18203	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 2 - Eye Diagram Test (TPS4)	15203	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 2 - Fall Time Test (D10.2)	123203	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Fall Time Test (HBR2CPAT)	120203	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Fall Time Test (Other Pattern)	129203	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 2 - Fall Time Test (PLTPAT)	124203	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Fall Time Test (PRBS 7)	121203	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Fall Time Test (PRBS 9)	122203	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Fall Time Test (Random Pattern)	128203	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Fall Time Test (TPS4)	125203	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Intra Pair Skew Test (D10.2)	503203	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Intra Pair Skew Test (HBR2CPAT)	500203	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Intra Pair Skew Test (TPS4)	505203	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Main Link Frequency Compliance Test (D10.2)	203203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (D10.2)	253203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (HBR2CPAT)	200203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (HBR2CPAT)	250203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (Other Pattern)	209203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (Other Pattern)	259203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (PRBS 7)	201203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 2 - Main Link Frequency Compliance Test (PRBS 7)	251203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (PRBS 9)	202203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (PRBS 9)	252203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (Random Pattern)	208203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (Random Pattern)	258203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (TPS4)	205203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Main Link Frequency Compliance Test (TPS4)	255203	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 2 - Non ISI Jitter Test (D10.2)	23203	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 2 - Non ISI Jitter Test (HBR2CPAT)	20203	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 2 - Non ISI Jitter Test (Other Pattern)	29203	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 2 - Non ISI Jitter Test (PRBS 7)	21203	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 2 - Non ISI Jitter Test (PRBS 9)	22203	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 2 - Non ISI Jitter Test (Random Pattern)	28203	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 2 - Non ISI Jitter Test (TPS4)	25203	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 2 - Peak to Peak Differential Voltage Test (HBR2CPAT)	60203	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Peak to Peak Differential Voltage Test (Other Pattern)	69203	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Peak to Peak Differential Voltage Test (PLTPAT)	64203	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Peak to Peak Differential Voltage Test (PRBS 7)	61203	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Peak to Peak Differential Voltage Test (PRBS 9)	62203	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 2 - Peak to Peak Differential Voltage Test (Random Pattern)	68203	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Peak to Peak Differential Voltage Test (TPS4)	65203	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (HBR2CPAT)	90203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (HBR2CPAT)	100203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (Other Pattern)	99203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (Other Pattern)	109203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (PLTPAT)	94203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (PLTPAT)	104203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (PRBS 7)	91203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (PRBS 7)	101203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (PRBS 9)	92203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (PRBS 9)	102203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (Random Pattern)	98203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (Random Pattern)	108203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (TPS4)	95203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Pre-Emphasis Level Test (TPS4)	105203	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 2 - Random Jitter Test (D10.2)	53203	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 2 - Random Jitter Test (HBR2CPAT)	50203	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Random Jitter Test (Other Pattern)	59203	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Random Jitter Test (PRBS 7)	51203	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Random Jitter Test (PRBS 9)	52203	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Random Jitter Test (Random Pattern)	58203	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Random Jitter Test (TPS4)	55203	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Rise Time Test (D10.2)	113203	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Rise Time Test (HBR2CPAT)	110203	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Rise Time Test (Other Pattern)	119203	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Rise Time Test (PLTPAT)	114203	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Rise Time Test (PRBS 7)	111203	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Rise Time Test (PRBS 9)	112203	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 2 - Rise Time Test (Random Pattern)	118203	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - Rise Time Test (TPS4)	115203	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 2 - SSC Modulation Deviation Test (D10.2)	353203	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 2 - SSC Modulation Deviation Test (HBR2CPAT)	350203	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 2 - SSC Modulation Deviation Test (Other Pattern)	359203	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 2 - SSC Modulation Deviation Test (PRBS 7)	351203	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 2 - SSC Modulation Deviation Test (PRBS 9)	352203	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 2 - SSC Modulation Deviation Test (Random Pattern)	358203	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 2 - SSC Modulation Deviation Test (TPS4)	355203	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 2 - SSC Modulation Frequency Test (D10.2)	303203	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 2 - SSC Modulation Frequency Test (HBR2CPAT)	300203	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 2 - SSC Modulation Frequency Test (Other Pattern)	309203	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 2 - SSC Modulation Frequency Test (PRBS 7)	301203	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 2 - SSC Modulation Frequency Test (PRBS 9)	302203	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 2 - SSC Modulation Frequency Test (Random Pattern)	308203	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 2 - SSC Modulation Frequency Test (TPS4)	305203	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 2 - Single-Ended Rise and Fall Time Mismatch Test (D10.2)	523203	To evaluate the difference in rise and fall times of the two single-ended signals in a given differential data lane of the eDP interface.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 2 - Total Jitter Test (D10.2)	33203	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Total Jitter Test (HBR2CPAT)	30203	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Total Jitter Test (Other Pattern)	39203	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Total Jitter Test (PRBS 7)	31203	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Total Jitter Test (PRBS 9)	32203	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Total Jitter Test (Random Pattern)	38203	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 - Total Jitter Test (TPS4)	35203	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 2 / Lane 3 - Inter Pair Skew Test (HBR2CPAT)	130206	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 2 / Lane 3 - Inter Pair Skew Test (Other Pattern)	139206	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 2 / Lane 3 - Inter Pair Skew Test (PRBS 7)	131206	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 2 / Lane 3 - Inter Pair Skew Test (PRBS 9)	132206	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 2 / Lane 3 - Inter Pair Skew Test (Random Pattern)	138206	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.
Lane 2 / Lane 3 - Inter Pair Skew Test (TPS4)	135206	To evaluate the skew, or time delay, between differential main link data lanes of the eDP interface.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 3 - AC Common Mode Noise Test (HBR2CPAT)	510204	To report common mode noise (unfiltered RMS) of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 3 - AC Common Mode Noise Test (TPS4)	515204	To report common mode noise (unfiltered RMS) of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Deterministic Jitter Test (D10.2)	43204	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Deterministic Jitter Test (HBR2CPAT)	40204	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Deterministic Jitter Test (Other Pattern)	49204	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Deterministic Jitter Test (PRBS 7)	41204	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Deterministic Jitter Test (PRBS 9)	42204	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Deterministic Jitter Test (Random Pattern)	48204	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Deterministic Jitter Test (TPS4)	45204	To evaluate the Deterministic Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Differential Voltage Level Test (HBR2CPAT)	70204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (HBR2CPAT)	80204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (Other Pattern)	79204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 3 - Differential Voltage Level Test (Other Pattern)	89204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (PLTPAT)	74204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (PLTPAT)	84204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (PRBS 7)	71204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (PRBS 7)	81204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (PRBS 9)	72204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (PRBS 9)	82204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (Random Pattern)	78204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (Random Pattern)	88204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (TPS4)	75204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Differential Voltage Level Test (TPS4)	85204	To evaluate the differential voltage level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Eye Diagram Test (D10.2)	13204	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 3 - Eye Diagram Test (HBR2CPAT)	10204	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 3 - Eye Diagram Test (Other Pattern)	19204	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 3 - Eye Diagram Test (PRBS 7)	11204	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 3 - Eye Diagram Test (PRBS 9)	12204	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 3 - Eye Diagram Test (Random Pattern)	18204	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 3 - Eye Diagram Test (TPS4)	15204	To evaluate the waveform to ensure that timing variabilities and amplitude trajectories are such to support the overall DisplayPort system objectives of Bit Error Rate in data transmission.
Lane 3 - Fall Time Test (D10.2)	123204	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Fall Time Test (HBR2CPAT)	120204	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Fall Time Test (Other Pattern)	129204	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Fall Time Test (PLTPAT)	124204	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Fall Time Test (PRBS 7)	121204	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Fall Time Test (PRBS 9)	122204	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Fall Time Test (Random Pattern)	128204	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Fall Time Test (TPS4)	125204	To evaluate the differential fall time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Intra Pair Skew Test (D10.2)	503204	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Intra Pair Skew Test (HBR2CPAT)	500204	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Intra Pair Skew Test (TPS4)	505204	To evaluate the skew, or time delay, between the n and p legs of the differential pairs of the eDP interface. These measurements can be useful in predicting the channels EMI/RFI performance.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 3 - Main Link Frequency Compliance Test (D10.2)	203204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (D10.2)	253204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (HBR2CPAT)	200204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (HBR2CPAT)	250204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (Other Pattern)	209204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (Other Pattern)	259204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (PRBS 7)	201204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (PRBS 7)	251204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (PRBS 9)	202204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (PRBS 9)	252204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (Random Pattern)	208204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (Random Pattern)	258204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (TPS4)	205204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Main Link Frequency Compliance Test (TPS4)	255204	To evaluate the data rate variation of the DUT's transmitted signal under all conditions is within the conformance limits.
Lane 3 - Non ISI Jitter Test (D10.2)	23204	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 3 - Non ISI Jitter Test (HBR2CPAT)	20204	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 3 - Non ISI Jitter Test (Other Pattern)	29204	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 3 - Non ISI Jitter Test (PRBS 7)	21204	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 3 - Non ISI Jitter Test (PRBS 9)	22204	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 3 - Non ISI Jitter Test (Random Pattern)	28204	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 3 - Non ISI Jitter Test (TPS4)	25204	To evaluate the amount of eDP Non ISI jitter accompanying the data transmission.
Lane 3 - Peak to Peak Differential Voltage Test (HBR2CPAT)	60204	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Peak to Peak Differential Voltage Test (Other Pattern)	69204	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Peak to Peak Differential Voltage Test (PLTPAT)	64204	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Peak to Peak Differential Voltage Test (PRBS 7)	61204	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Peak to Peak Differential Voltage Test (PRBS 9)	62204	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Peak to Peak Differential Voltage Test (Random Pattern)	68204	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Peak to Peak Differential Voltage Test (TPS4)	65204	To evaluate the peak to peak differential voltage of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (HBR2CPAT)	90204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (HBR2CPAT)	100204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (Other Pattern)	99204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (Other Pattern)	109204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (PLTPAT)	94204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (PLTPAT)	104204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (PRBS 7)	91204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (PRBS 7)	101204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (PRBS 9)	92204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (PRBS 9)	102204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 3 - Pre-Emphasis Level Test (Random Pattern)	98204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (Random Pattern)	108204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (TPS4)	95204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Pre-Emphasis Level Test (TPS4)	105204	To evaluate the pre-emphasis level of the DUT's transmitted signal is within the conformance limits.
Lane 3 - Random Jitter Test (D10.2)	53204	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Random Jitter Test (HBR2CPAT)	50204	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Random Jitter Test (Other Pattern)	59204	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Random Jitter Test (PRBS 7)	51204	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Random Jitter Test (PRBS 9)	52204	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Random Jitter Test (Random Pattern)	58204	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Random Jitter Test (TPS4)	55204	To evaluate the Random Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Rise Time Test (D10.2)	113204	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 3 - Rise Time Test (HBR2CPAT)	110204	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Rise Time Test (Other Pattern)	119204	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Rise Time Test (PLTPAT)	114204	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Rise Time Test (PRBS 7)	111204	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Rise Time Test (PRBS 9)	112204	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Rise Time Test (Random Pattern)	118204	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - Rise Time Test (TPS4)	115204	To evaluate the differential rise time of the main link data lanes of the eDP interface. These measurement can be useful in predicting the channels EMI/RFI performance.
Lane 3 - SSC Modulation Deviation Test (D10.2)	353204	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 3 - SSC Modulation Deviation Test (HBR2CPAT)	350204	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 3 - SSC Modulation Deviation Test (Other Pattern)	359204	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 3 - SSC Modulation Deviation Test (PRBS 7)	351204	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 3 - SSC Modulation Deviation Test (PRBS 9)	352204	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 3 - SSC Modulation Deviation Test (Random Pattern)	358204	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 3 - SSC Modulation Deviation Test (TPS4)	355204	To evaluate the range of SSC down-spreading of the DUT's transmitted signal in ppm is within the conformance limits.
Lane 3 - SSC Modulation Frequency Test (D10.2)	303204	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 3 - SSC Modulation Frequency Test (HBR2CPAT)	300204	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Lane 3 - SSC Modulation Frequency Test (Other Pattern)	309204	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 3 - SSC Modulation Frequency Test (PRBS 7)	301204	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 3 - SSC Modulation Frequency Test (PRBS 9)	302204	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 3 - SSC Modulation Frequency Test (Random Pattern)	308204	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 3 - SSC Modulation Frequency Test (TPS4)	305204	To evaluate the frequency of the SSC modulation and to validate it falls with specification limits.
Lane 3 - Single-Ended Rise and Fall Time Mismatch Test (D10.2)	523204	To evaluate the difference in rise and fall times of the two single-ended signals in a given differential data lane of the eDP interface.
Lane 3 - Total Jitter Test (D10.2)	33204	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Total Jitter Test (HBR2CPAT)	30204	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Total Jitter Test (Other Pattern)	39204	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Total Jitter Test (PRBS 7)	31204	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Total Jitter Test (PRBS 9)	32204	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Total Jitter Test (Random Pattern)	38204	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.
Lane 3 - Total Jitter Test (TPS4)	35204	To evaluate the Total Jitter accompanying the data transmission at either an explicit bit error rate of 1E-9 or through an approved estimation technique . This measurement is a data time interval error (Data-TIE) jitter measurement.

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Macro	100201	Selects:100201001,100201002,100201003,100201004
Macro	100202	Selects:100202001,100202002,100202003,100202004
Macro	100203	Selects:100203001,100203002,100203003,100203004
Macro	100204	Selects:100204001,100204002,100204003,100204004
Macro	101201	Selects:101201001,101201002,101201003,101201004
Macro	101202	Selects:101202001,101202002,101202003,101202004
Macro	101203	Selects:101203001,101203002,101203003,101203004
Macro	101204	Selects:101204001,101204002,101204003,101204004
Macro	102201	Selects:102201001,102201002,102201003,102201004
Macro	102202	Selects:102202001,102202002,102202003,102202004
Macro	102203	Selects:102203001,102203002,102203003,102203004
Macro	102204	Selects:102204001,102204002,102204003,102204004
Macro	104201	Selects:104201001,104201002,104201003,104201004
Macro	104202	Selects:104202001,104202002,104202003,104202004
Macro	104203	Selects:104203001,104203002,104203003,104203004
Macro	104204	Selects:104204001,104204002,104204003,104204004
Macro	105201	Selects:105201001,105201002,105201003,105201004
Macro	105202	Selects:105202001,105202002,105202003,105202004
Macro	105203	Selects:105203001,105203002,105203003,105203004
Macro	105204	Selects:105204001,105204002,105204003,105204004
Macro	108201	Selects:108201001,108201002,108201003,108201004
Macro	108202	Selects:108202001,108202002,108202003,108202004
Macro	108203	Selects:108203001,108203002,108203003,108203004
Macro	108204	Selects:108204001,108204002,108204003,108204004
Macro	109201	Selects:109201001,109201002,109201003,109201004
Macro	109202	Selects:109202001,109202002,109202003,109202004
Macro	109203	Selects:109203001,109203002,109203003,109203004
Macro	109204	Selects:109204001,109204002,109204003,109204004
Macro	80201	Selects:80201001,80201002,80201003,80201004
Macro	80202	Selects:80202001,80202002,80202003,80202004
Macro	80203	Selects:80203001,80203002,80203003,80203004

Table 4   Test IDs and Names (continued)

Name	TestID	Description
Macro	80204	Selects:80204001,80204002,80204003,80204004
Macro	81201	Selects:81201001,81201002,81201003,81201004
Macro	81202	Selects:81202001,81202002,81202003,81202004
Macro	81203	Selects:81203001,81203002,81203003,81203004
Macro	81204	Selects:81204001,81204002,81204003,81204004
Macro	82201	Selects:82201001,82201002,82201003,82201004
Macro	82202	Selects:82202001,82202002,82202003,82202004
Macro	82203	Selects:82203001,82203002,82203003,82203004
Macro	82204	Selects:82204001,82204002,82204003,82204004
Macro	84201	Selects:84201001,84201002,84201003,84201004
Macro	84202	Selects:84202001,84202002,84202003,84202004
Macro	84203	Selects:84203001,84203002,84203003,84203004
Macro	84204	Selects:84204001,84204002,84204003,84204004
Macro	85201	Selects:85201001,85201002,85201003,85201004
Macro	85202	Selects:85202001,85202002,85202003,85202004
Macro	85203	Selects:85203001,85203002,85203003,85203004
Macro	85204	Selects:85204001,85204002,85204003,85204004
Macro	88201	Selects:88201001,88201002,88201003,88201004
Macro	88202	Selects:88202001,88202002,88202003,88202004
Macro	88203	Selects:88203001,88203002,88203003,88203004
Macro	88204	Selects:88204001,88204002,88204003,88204004
Macro	89201	Selects:89201001,89201002,89201003,89201004
Macro	89202	Selects:89202001,89202002,89202003,89202004
Macro	89203	Selects:89203001,89203002,89203003,89203004
Macro	89204	Selects:89204001,89204002,89204003,89204004
Offline Capture Waveform	101	

4 Instruments

The following table shows the instruments used by this application. The name is required by various remote interface methods.

- Instrument Name — The name to use as a parameter in remote interface commands.
- Description — The description of the instrument.

For example, if an application uses an oscilloscope and a pulse generator, then you would expect to see something like this in the table below:

Table 5   Example Instrument Information

Name	Description
scope	The primary oscilloscope.
Pulse	The pulse generator used for Gen 2 tests.

and you would be able to remotely control an instrument using:

```
ARSL syntax (replace [description] with actual parameter)
----------------------------------------------------------------------
arsl -a ipaddress -c "SendScpiCommandCustom 'Command=[scpi
command];Timeout=100;Instrument=pulsegen'"

arsl -a ipaddress -c "SendScpiQueryCustom 'Command=[scpi
query];Timeout=100;Instrument=pulsegen'"


C# syntax (replace [description] with actual parameter)
----------------------------------------------------------------------
SendScpiCommandOptions commandOptions = new SendScpiCommandOptions();
commandOptions.Command = "[scpi command]";
commandOptions.Instrument = "[instrument name]";
commandOptions.Timeout = [timeout];
remoteAte.SendScpiCommand(commandOptions);

SendScpiQueryOptions queryOptions = new SendScpiQueryOptions();
queryOptions.Query = "[scpi query]";
queryOptions.Instrument = "[instrument name]";
```

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```
queryOptions.Timeout = [timeout];
remoteAte.SendScpiQuery(queryOptions);
```

Here are the actual instrument names used by this application:

> **NOTE** The file, "InstrumentInfo.txt", which may be found in the same directory as this help file, contains all of the information found in the table below in a format suitable for parsing.

Table 6   Instrument Names

Instrument Name	Description
Infiniium	The primary oscilloscope

5 Message IDs

During the normal course of operation, an application displays multiple message prompts. The application's remote interface exposes a callback capability which enables remote clients to receive the text found in the prompt and to programmatically select the desired response (OK, Cancel, etc.). In order to determine which message is being received, the remote program could parse the message and look for key words. However, because message text is subject to change, a more reliable approach is to use the "message ID" that is attached to the more frequently-seen messages. The following table shows the IDs of the messages that this application may prompt during nominal operation.

For example, if the application may display the following prompt:
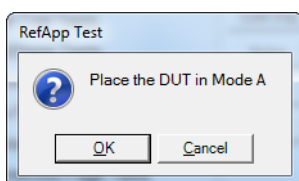
then you would expect to see something like this in the table below:

Message	ID	Responses	Usage
DUT mode message	313AEE2F-9EF0-476f-A2EB-29A5C7DE686F	OK=action completed and proceed, Cancel = abort test	App

- Message — A summary of the message in the prompt.
- ID — A unique code that will never change for this prompt, even if the message text changes (assuming the underlying purpose is maintained).
- Responses — The buttons on the prompt and their actions.
- Usage — The scope of the message:
  - "Common" — This message/ID may be used by other apps.

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· "App" — This message/ID is unique to this app.

· "<testID>" — This message/ID is unique to this test ID.

A remote client would then structure the code in its message callback handler as shown below to manage message identification:

```
private static void OnSimpleMessage(object sender, MessageEventArgs e)
{
  if (e.ID == "313AEE2F-9EF0-476f-A2EB-29A5C7DE686F")
  {
    // Add code here to set the DUT in Mode A

    e.Response = DialogResult.OK;
  }
}
```

Here are actual message IDs used by this application:

| NOTE | The file, "MessageInfo.txt", which may be found in the same directory as this help file, contains all of the information found in the table below in a format suitable for parsing. |

Table 7   Message IDs

Message	ID	Responses	Usage
Acq Limit: Can't determine minimum bandwidth	25A86458-151E-413D-B890-FC30CFD5ECAA	OK	Instrument
Activating limit will conflict with existing resutls	31A39751-6019-41de-89DF-59DB239DF978	OK=delete conflicting results, Cancel=cancel activation	Instrument
Already running tests	022467B0-6E08-40eb-B4D4-BBB018FBFBC7	OK	Instrument
App startup aborted	C2B67F67-E5D5-4845-8B63-443781223010	OK	Instrument
Can't set memory depth	FFFF1129-BD83-4318-993E-64C94033CEC4	OK=skip step and continue, Cancel=abort test	Instrument
Channel Setup: Unknown scope channel	CDE944EB-F440-4CB1-AFDC-7596461BCD86	OK	Instrument
Compliance/Debug mode change	9C72A970-8D7D-4b37-9787-48AEEA5DC3F1	OK=change mode, Cancel=abort action	Instrument
Confirmation Required	37437505-160C-4cc8-BA06-093C12994C1E	OK=continue, Cancel=abort test	Instrument
Connection change	879629E6-78FA-4a87-B247-A9DB4F0D7330	Abort=abort run, Retry=connection changed - continue run, Ignore=connection not chagned - continue run	Instrument

Table 7   Message IDs (continued)

Message	ID	Responses	Usage
Debug pause (messages vary)	50B66A97-A6A9-413f-8329-76DFAC492FD6	OK=resume, Cancel=abort run	Instrument
End of run summary	602F9866-F975-42b7-842C-D8447E5E3FCB	OK	Instrument
End of run summary (test aborted)	124580E4-4486-42d4-B908-C6D0FB2AEE93	OK	Instrument
Error during CSV file generation	C88B1C64-8334-4b15-8727-81F5E2BA2ED4	OK	Instrument
Error during app exit	81112706-F720-4787-81D3-B22A9B692B41	OK	Instrument
Expected signal not found	86C74779-322E-4585-A07A-26A2C8FAAC84	Abort=abort test, Retry=retry failed action, Ignore=skip failed step	Instrument
Expected signal not found	7957D5B8-E62D-4224-A7DD-70361E816A43	Retry=retry failed action, Cancel=abort test	Instrument
InfiniiSim: Not available because scope default prevented	B8461A2C-9F5F-4AF3-94C1-DF77080D517A	OK	Instrument
InfiniiSim: Scope doesn't support settings found in project	C9BC2205-8041-448b-AF31-CF602183E989	OK	Instrument
InfiniiSim: Unknown scope channel	4E5ECAF6-867C-47B3-982D-5F07E2090703	OK	Instrument
Measurement Server no Measure Workers declared	54A8428D-8E22-4286-AC88-7495821ABA77	OK=retry, Cancel=abort run	Instrument
No test selected	B5D233AD-9EB4-4ac2-A443-A30A13643978	OK	Instrument
PrecisionProbe and InfiniiSim controllers turned off after config change	B4477006-D6D1-4375-9FF7-D8177FFC1BF9	OK	Instrument
PrecisionProbe/PrecisionCable: Not available because scope default prevented	6E60C9F8-8FBF-419C-B70A-B666FBDE3677	OK	Instrument
PrecisionProbe/PrecisionCable: Scope doesn't support settings found in project	2FC3B6FA-E28C-4700-9F46-4ABBA86A0D90	OK	Instrument
PrecisionProbe/PrecisionCable: Switch Controller is enabled	22F46DA8-89AE-4370-A57C-571DCF5BB87E	OK	Instrument
PrecisionProbe/PrecisionCable: Unknown scope channel	6788685B-9E88-47E6-BAE6-862F5BF3C9BA	OK	Instrument

Table 7   Message IDs (continued)

Message	ID	Responses	Usage
Project loaded as read-only (reason)	98C785F8-D24F-4758-A18D-1CCE61F25371	OK	Instrument
Project loaded with errors	58AD7A02-1E63-4d77-BC6C-6EF3E37AAD5B	OK	Instrument
Project not loaded	B2615E9C-5ED7-4db7-AEAF-2BC25C62B656	OK	Instrument
Project save failed (unauthorized access)	89DCC194-6254-4902-AE63-B7CCD12C8B2A	OK	Instrument
Run paused	FE2CF871-6D4A-4080-8FF9-770075590D9F	OK=resume, Cancel=abort run	Instrument
Setting change requires result deletion	8732A3AB-142C-47e5-86EA-DB737F415DDE	OK=delete results; Cancel=abort change	Instrument
Store mode change requires result deletion	884CDFDE-605E-4d04-B8FD-9B181E7FA468	OK=delete results, Cancel=abort change	Instrument
Switch Matrix controller turned off after config change	FC95EBAA-F33F-4eae-90BB-6A6A8F16E2DF	OK	Instrument
Switch Matrix: Auto mode unavailable after config change	6E5589DC-E073-4818-9E8A-782A75898475	OK	Instrument
Switch Matrix: Auto mode unavailable for model, all settings will be reset	F78BD2E2-BF29-42e0-98F8-23B6CE565B08	OK=go auto do reset, Cancel=abort action	Instrument
Switch Matrix: Confirm Auto mode	D5E1A12E-6218-4416-8451-5F9415D924BF	OK=go auto, Cancel=stay manual	Instrument
Switch Matrix: Obsolete items in settings discarded	0C45BD20-E0C2-481e-A3B6-9C1A26C2103A	OK	Instrument
Switch Matrix: Reconnect drivers	047FE44F-B251-49fa-B3C7-5590317230CD	Yes=use saved addresses, No=prompt for new addresses, Cancel=reset all settings	Instrument
Switch Matrix: Remove all InfiniiSim settings	C5560182-73BE-4901-941E-3DAEC9F07B33	OK=remove, Cancel=abort action	Instrument
Switch Matrix: User cancelled settings load	50F3FB70-AA6B-488e-8CFA-62CDA756F746	OK	Instrument
SwitchMatrix: Correction reset due to application route change	95FEA629-3BE1-4288-BA34-426516018B07	OK=Accept new routing, Cancel=Reset switch matrix settings	Instrument
SwitchMatrix: Instrument already connected to another driver	08556148-4D63-4edd-B894-22916F39849A	OK	Instrument

Table 7   Message IDs (continued)

Message	ID	Responses	Usage
SwitchMatrix: Max num drivers exceeded	7D8994AB-FCC2-4294-87B3-19B972BB6510	OK	Instrument
SwitchMatrix: Reset after drive reconnect fail	CF3E93B6-77FA-4FD7-B656-D286BE1C7C75	OK	Instrument
SwitchMatrix: Reset after drive reconnect fail	D298A4B8-F077-49BE-9CB2-AE6C14FB4705	OK	Instrument
SwitchMatrix: Unexpected multi-SPDT module	2723591D-55A9-44F3-9318-B732995D9427	OK	Instrument
SwitchMatrix: Unknown current switch state	ECE6535B-5C1A-4688-9E45-FB255435CC92	OK	Instrument
Unknown EEyeLocation parameter	FCA1C61B-D2EA-4671-AD48-9C080A6C6039	OK	Instrument
Upgrade app to open project	794C6148-ADF4-4b24-895D-74D94B76F8AE	OK	Instrument

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